

EN 55022:2010
EN 55024:2010
EN 61000-3-2:2006 + A1:2009 + A2:2009
EN 61000-3-3:2008

TEST REPORT

For

YEALINK (XIAMEN) NETWORK TECHNOLOGY CO., LTD

4th-5th Floor, South Building, NO. 63 WangHai Road, 2nd Software Park, Xiamen, China

Model: SIP-T26P, SIP-T26

Report Type: Amended Report	Product Type: IP PHONE
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DOCUMENT REVISION HISTORY

Revision Number	Report Number	Description of Revision	Date of Issue
0	RSZ110725003-01	Original Report	2011-09-19
1	RSZ121211013-01A1	Amended Report	2012-12-18
2	RSZ130614002-01A2	Amended Report	2013-07-01

Note:

This is an amended report application based on RSZ121211013-01A1, the details as below

Adding two new adapters: OH-1006B0501200U-VDE and NSA6EE-050120

Based on the above difference, it affects test items “Conducted Disturbance” and “Radiated Disturbance”, so the related test items were performed, related setup photos and EUT photos were updated, and the other test data and photos were copied from the original report RSZ121211013-01A1 that issued on 2012-12-18.

GENERAL INFORMATION

Product Description for Equipment Under Test (EUT)

The YEALINK (XIAMEN) NETWORK TECHNOLOGY CO., LTD. 's product, model number: SIP-T26P (the "EUT") in this report is a IP PHONE, which was measured approximately: 27.0 cm (L) x 19.0 cm (W) x 15.0 cm (H), rated input voltage: DC 5V from adapter. The highest operating frequency is 125 MHz.

Adapter 1 (original) information:

Model: OH-1048A0501200U2-VDE

Input: AC 100-240V, 50/60Hz, 250mA

Output: DC 5V, 1.2A

Adapter 2 (new) information:

Model: OH-1006B0501200U-VDE

Input: AC 100-240V, 50/60Hz, 250mA

Output: DC 5V, 1.2A

Adapter 3 (new) information:

Model: NSA6EE-050120

Input: AC 100-240V, 50/60Hz, 0.2A

Output: DC 5V, 1.2A

Note: The product IP PHONE, model SIP-T26 is electrically identical with the model SIP-T26P which is selected to test, the difference between them is explained in the attached declaration letter.

**All measurement and test data in this report was gathered from production sample serial number: 1306026 (Assigned by BACL, Shenzhen). The EUT supplied by applicable was received on 2013-06-14.*

Objective

This test report is prepared on behalf of YEALINK (XIAMEN) NETWORK TECHNOLOGY CO., LTD. in accordance with EN 55022: Information technology equipment – Radio disturbance characteristics – Limits and methods of measurement. EN 55024: Information technology equipment- Immunity characteristics – Limits and methods of measurement, EN 61000-3-2, Limits – Limits for harmonic current emissions (equipment input current up to and including 16 A per phase), and also in accordance with EN 61000-3-3, Limits Section 3; Limitation of voltage fluctuations and flicker in low-voltage supply systems for equipment with rated current <16A.

The objective of the manufacturer is to determine compliance with EN 55022, EN 55024, EN 61000-3-2 and EN 61000-3-3.

Related Submittal(s)/Grant(s)

No related submittal(s).

Test Methodology

All measurements contained in this report were conducted with CISPR 16-1-1:2010, specification for radio disturbance and immunity measuring apparatus and methods P1-1: radio disturbance and immunity measuring apparatus measuring apparatus. CISPR 16-1-4:2012, Specification for radio disturbance and immunity measuring apparatus and methods-Part 1-4: Radio disturbance and immunity measuring apparatus -Ancillary equipment -Radiated disturbances. CISPR 16-2-1:2010, specification for radio disturbance and immunity measuring apparatus and methods P2-1: methods of measurement of disturbance and immunity conducted disturbance measurements. CISPR 16-2-3:2010, specification for radio disturbance and immunity measuring apparatus and methods P2-3 methods of measurement of disturbances and immunity radiated disturbance measurements. CISPR 16-4-2:2011, Specification for radio disturbance and immunity measuring apparatus and methods-Part 4-2: Uncertainties, statistics and limit modeling-Uncertainty in EMC measurements

All radiated and conducted emissions measurements were performed at Bay Area Compliance Laboratories Corp. (Shenzhen). The radiated testing was performed at an antenna-to-EUT distance of 3 Meters.

Test Facility

The test site used by Bay Area Compliance Laboratories Corp. (Shenzhen) to collect test data is located on the 6/F, the 3rd Phase of WanLi Industrial Building, ShiHua Road, FuTian Free Trade Zone Shenzhen, Guangdong, China.

Test site at Bay Area Compliance Laboratories Corp. (Shenzhen) has been fully described in reports submitted to the Federal Communication Commission (FCC). The details of these reports have been found to be in compliance with the requirements of Section 2.948 of the FCC Rules on December 06, 2010. The facility also complies with the radiated and AC line conducted test site criteria set forth in ANSI C63.4-2009.

The Federal Communications Commission has the reports on file and is listed under FCC Registration No.: 382179. The test site has been approved by the FCC for public use and is listed in the FCC Public Access Link (PAL) database.

SYSTEM TEST CONFIGURATION

Justification

The system was configured for testing in a manufacturer testing fashion.

Equipment Modifications

No modification was made to the EUT tested.

Support Equipment List and Details

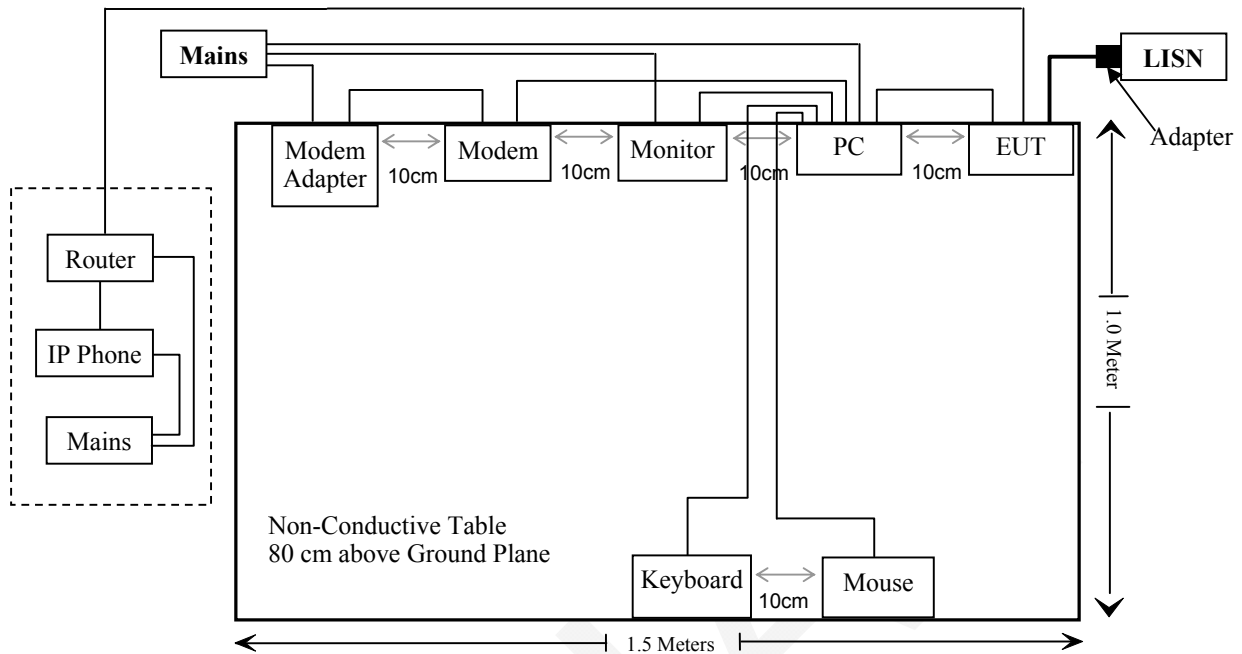
Manufacturer	Description	Model	Serial Number
DELL	PC	127BPX2	N/A
DELL	Monitor	E178WFPC	CN-OWY564-64180-7C4-2SQH
DELL	Mouse	MOC5UO	G1B0096D
DELL	Keyboard	L100	CNORH656658907BL04TY
Sagemcom	Router	N/A	N/A
Yealink	IP phone	SIP-T41P	N/A
ECOM	Modem	5600pbs	N/A

External I/O Cable

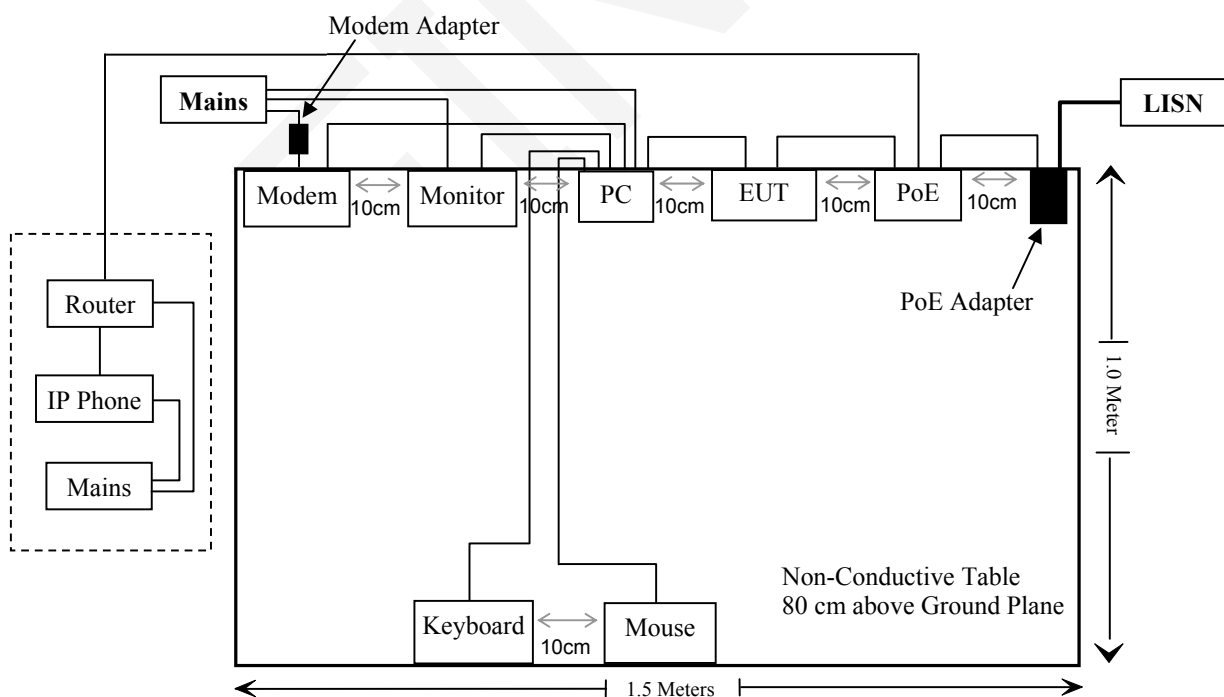
Cable Description	Length (m)	From/Port	To
Shielded Undetachable K/B Cable	1.5	K/B	PC
Shielded Undetachable Mouse Cable	1.5	Mouse	PC
Shielded Undetachable VGA Cable	1.5	Monitor	PC
Unshielded Detachable AC Cable	1.0	Main	Monitor
Unshielded Detachable RS232 Cable	1.5	Modem	PC
Unshielded Detachable RJ45 Cable	1.5	EUT	PC
Unshielded Detachable DC Cable	1.8	Main	EUT
Unshielded Detachable AC Cable	1.0	Main	PC
Unshielded Detachable RJ45 Cable	10	EUT	Router
Unshielded Detachable DC Cable	1.5	Main	Router
Unshielded Detachable DC Cable	1.8	Main	IP Phone
Unshielded Detachable RJ45 Cable	1.5	Router	IP Phone

Block Diagram of Test Setup

1) Adapter power supply:



2) PoE power supply:



SUMMARY OF TEST REPORT**EN 55022**

RULE	DESCRIPTION	RESULTS
§ 5.1	Conducted Disturbance at Mains Terminals	Compliance
§ 5.2	Conducted Disturbance at Telecommunication Port	Compliance
§ 6	Radiated Disturbance	Compliance

EN 55024

RULE	DESCRIPTION	RESULTS
§4.2.1	Electrostatic Discharge IEC 61000-4-2	Compliance
§4.2.2	Electrical Fast Transients IEC 61000-4-4	Compliance
§4.2.3.1	Continuous Radiated Disturbance IEC 61000-4-3	Compliance
§4.2.3.2	Continuous Conducted Disturbance IEC 61000-4-6	Compliance
§4.2.4	Power Frequency Magnetic Fields IEC 61000-4-8	Compliance
§4.2.5	Surges IEC 61000-4-5	Compliance
§4.2.6	Voltage Dips And Interruptions, IEC 61000-4-11	Compliance

EN 61000-3-2

RULE	DESCRIPTION	RESULTS
	Harmonic Current Emissions	Compliance

EN 61000-3-3

RULE	DESCRIPTION	RESULTS
	Voltage Fluctuation and Flicker	Compliance

EN 55022 §5.1 & §5.2-CONDUCTED DISTURBANCE AT MAINS TERMINALS AND TELECOMMUNICATION PORT

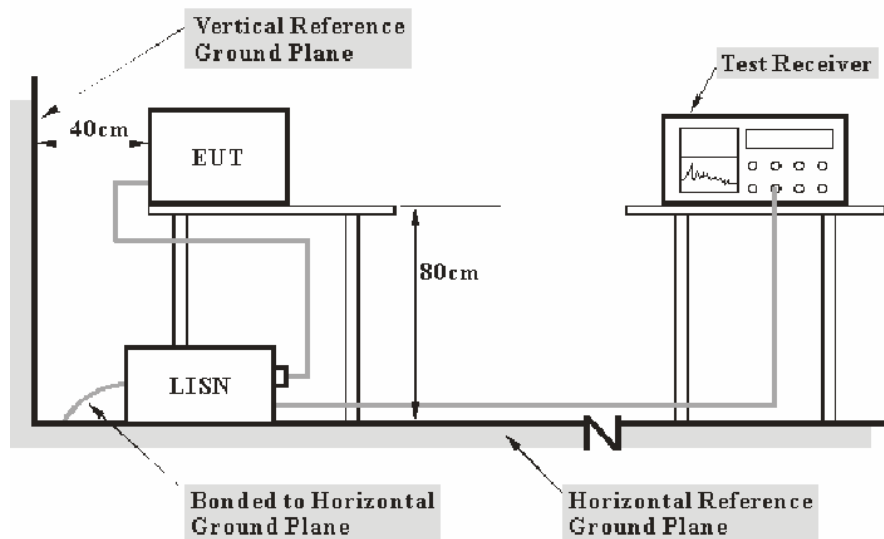
Measurement Uncertainty

Input quantities to be considered for conducted disturbance measurements maybe receiver reading, attenuation of the connection between AMN/ISN and receiver, AMN/ISN voltage division factor, AMN/ISN VDF frequency interpolation and receiver related input quantities, etc.

Based on CISPR 16-4-2:2011, the expended combined standard uncertainty of conducted disturbance test at Bay Area Compliance Laboratories Corp. (Shenzhen) is shown as below. And the uncertainty will not be taken into consideration for the test data recorded in the report

Port	Measurement uncertainty
AC Mains	3.26 dB (k=2, 95% level of confidence)
CAT 3	3.70 dB (k=2, 95% level of confidence)
CAT 5	3.86 dB (k=2, 95% level of confidence)
CAT 6	4.64 dB (k=2, 95% level of confidence)

Test System Setup



- Note: 1. Support units were connected to second LISN.
 2. Both of LISNs (AMN) 80 cm from EUT and at the least 80 cm from other units and other metal planes support units.

The setup of EUT is according with CISPR 16-2-1:2010 measurement procedure. The related limit was specified in the EN 55022 Class B.

The external I/O cables were draped along the test table and formed a bundle 30 to 40 cm long in the middle.

The spacing between the peripherals was 10 cm.

The adapter was connected to an AC 230V/50 Hz power source.

EMI Test Receiver Setup

The EMI test receiver was set to investigate the spectrum from 150 kHz to 30 MHz.

During the conducted emission test, the EMI test receiver was set with the following configurations:

Frequency Range	IF B/W
150 kHz – 30 MHz	9 kHz

Test Equipment List and Details

Manufacturer	Description	Model	Serial Number	Calibration Date	Calibration Due Date
Rohde & Schwarz	EMI Test Receiver	ESCS30	100176	2013-06-17	2014-06-17
Rohde & Schwarz	L.I.S.N.	ESH2-Z5	892107/021	2012-08-22	2013-08-21
Schwarzbeck	ISN	NTFM 8158	cat 5-8158-0010	2012-11-05	2013-11-05
Rohde & Schwarz	Transient Limiter	ESH3Z2	DE25985	2012-08-09	2013-08-09
Rohde & Schwarz	LISN	ENV216	3560.6650.12-101613-Yb	2013-05-07	2014-05-07

* **Statement of Traceability:** Bay Area Compliance Laboratories Corp. (Shenzhen) attests that all calibrations have been performed in accordance to requirements that traceable to National Primary Standards and International System of Units (SI).

Test Procedure

During the conducted emission test, the adapter was connected to the outlet of the LISN.

Maximizing procedure was performed on the six (6) highest emissions to ensure EUT compliance using all installation combination.

All data was recorded in the Quasi-peak and average detection mode.

Test Results Summary

According to the recorded data in following table, with the worst margin reading of:

1.3 dB at 23.130000 MHz in the Line conducted mode (adapter 2 power supply)

Refer to CISPR16-4-2:2011 and CISPR 16-4-1:2009, the measured level is in compliance with the limit if

$$L_m + U_{(Lm)} \leq L_{lim} + U_{cispr}$$

in BACL, $U_{(Lm)}$ is less than U_{cispr} , if L_m is less than L_{lim} , it implies that the EUT complies with the limit.

Test Data**Environmental Conditions**

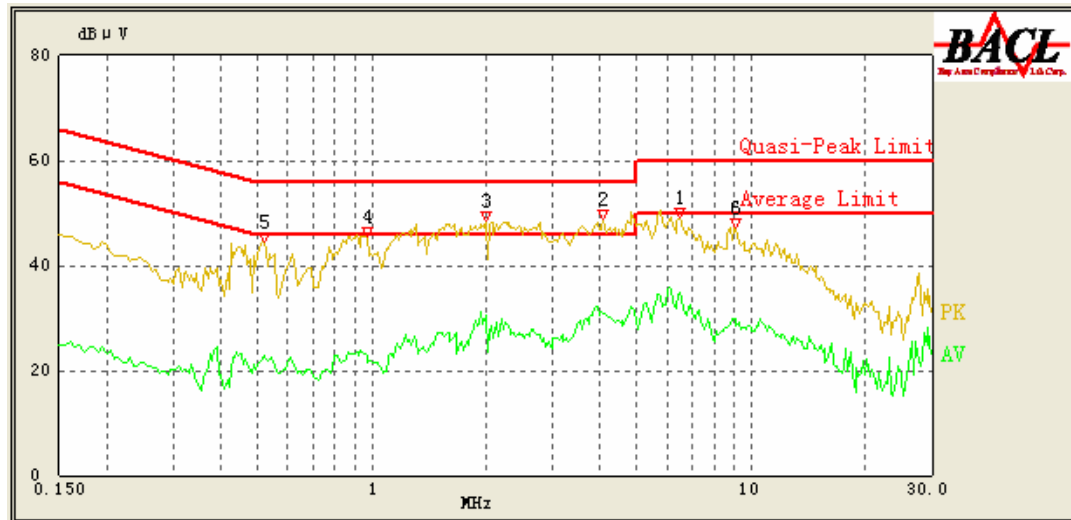
Temperature:	25 °C
Relative Humidity:	56 %
ATM Pressure:	100.0 kPa

The testing was performed by Joson Xiao on 2013-06-20.

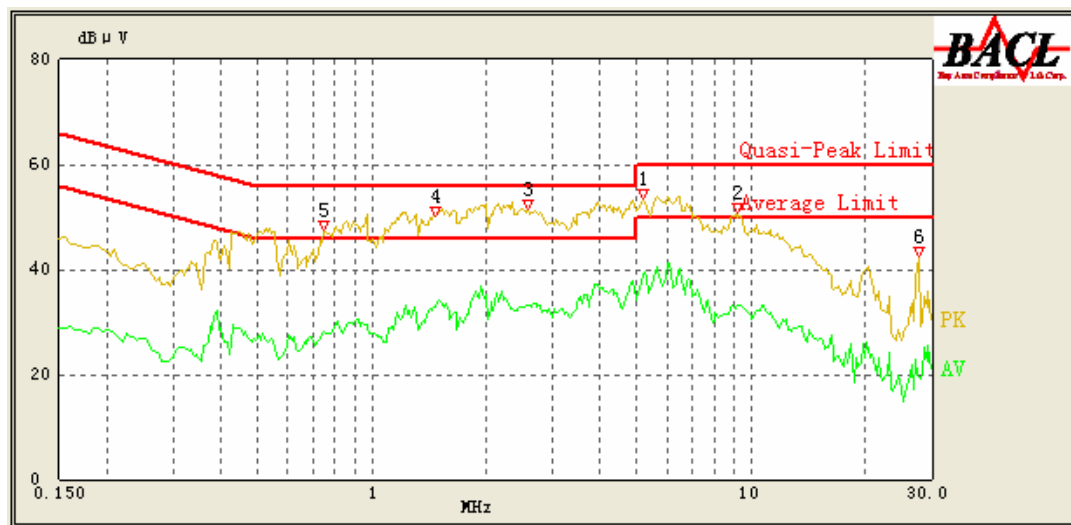
Test Mode: Talking

1) Adapter 1 power supply:

AC 230V/50 Hz, Line:



Frequency (MHz)	Corrected Amplitude (dBμV)	Correction Factor (dB)	Limit (dBμV)	Margin (dB)	Detector (PK/Ave./QP)
6.510	34.93	10.10	50.00	15.07	Ave.
4.070	30.91	10.10	46.00	15.09	Ave.
2.005	30.53	10.10	46.00	15.47	Ave.
0.970	39.43	10.10	56.00	16.57	QP
2.000	39.40	10.10	56.00	16.60	QP
4.085	38.19	10.10	56.00	17.81	QP
6.490	40.45	10.10	60.00	19.55	QP
9.155	28.54	10.10	50.00	21.46	Ave.
9.110	36.98	10.10	60.00	23.02	QP
0.520	22.91	10.10	46.00	23.09	Ave.
0.970	22.74	10.10	46.00	23.26	Ave.
0.520	32.47	10.10	56.00	23.53	QP

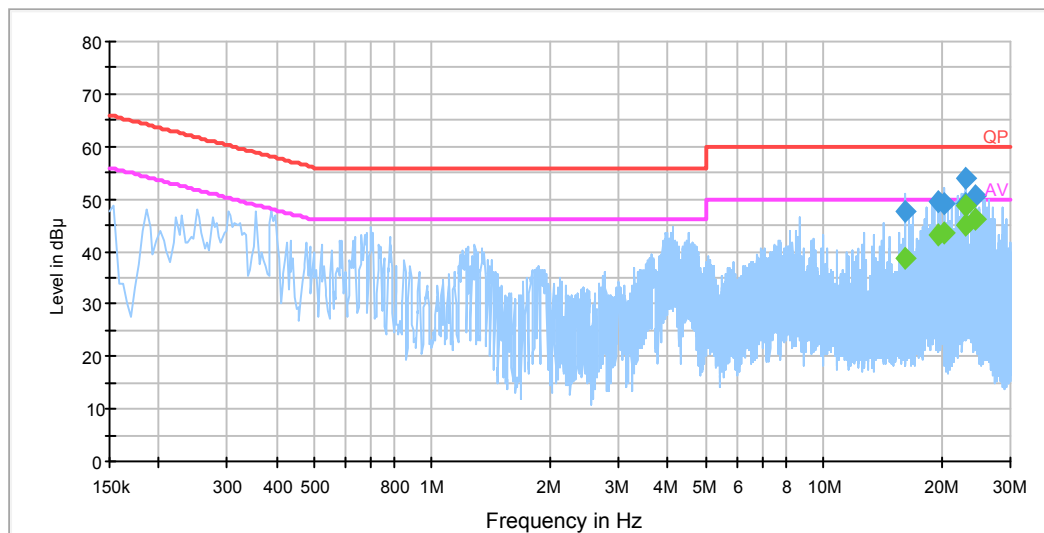
AC 230V/50 Hz, Neutral:

Frequency (MHz)	Corrected Amplitude (dBμV)	Correction Factor (dB)	Limit (dBμV)	Margin (dB)	Detector (PK/Ave./QP)
5.195	38.67	10.10	50.00	11.33	Ave.
1.470	44.66	10.10	56.00	11.34	QP
2.580	44.18	10.10	56.00	11.82	QP
2.585	33.26	10.10	46.00	12.74	Ave.
1.470	33.00	10.10	46.00	13.00	Ave.
5.195	46.83	10.10	60.00	13.17	QP
0.750	41.19	10.10	56.00	14.81	QP
9.180	44.52	10.10	60.00	15.48	QP
9.225	33.02	10.10	50.00	16.98	Ave.
0.750	28.01	10.10	46.00	17.99	Ave.
27.345	19.68	10.10	50.00	30.32	Ave.
27.700	23.59	10.10	60.00	36.41	QP

2) Adapter 2 power supply:

AC 230V/50 Hz, Line:

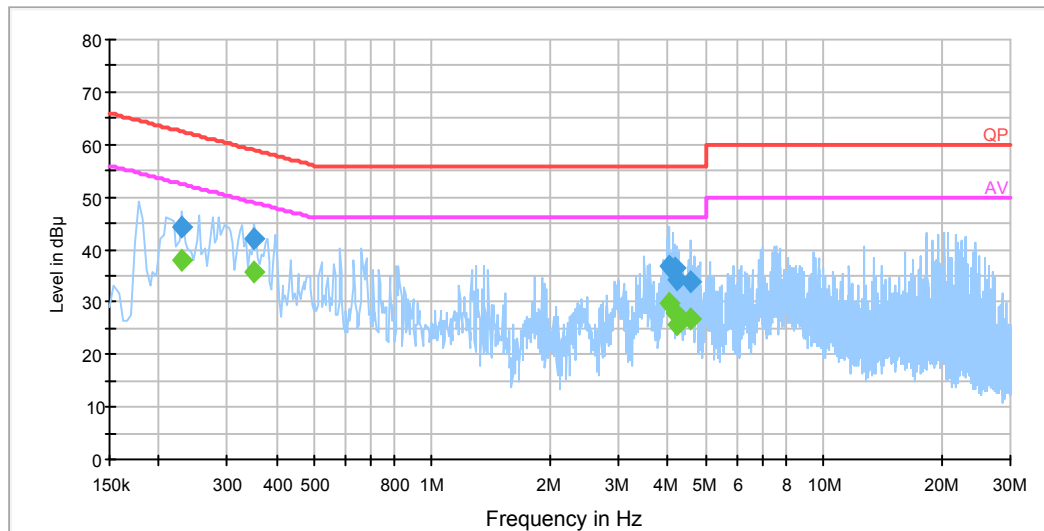
EMI Auto Test L



Frequency (MHz)	Corrected Amplitude (dBμV)	Correction Factor (dB)	Limit (dBμV)	Margin (dB)	Detector (PK/Ave./QP)
16.226000	47.5	20.0	60.0	12.5	QP
19.706000	49.5	20.0	60.0	10.5	QP
20.318000	49.3	20.0	60.0	10.7	QP
23.070000	49.3	20.1	60.0	10.7	QP
23.130000	54.0	20.1	60.0	6.0	QP
24.350000	50.4	20.2	60.0	9.6	QP
16.226000	38.6	20.0	50.0	11.4	Ave.
19.706000	43.3	20.0	50.0	6.7	Ave.
20.318000	43.6	20.0	50.0	6.4	Ave.
23.070000	44.9	20.1	50.0	5.1	Ave.
23.130000	48.7	20.1	50.0	1.3*	Ave.
24.350000	46.0	20.2	50.0	4.0	Ave.

AC 230V/50 Hz, Neutral:

EMI Auto Test N

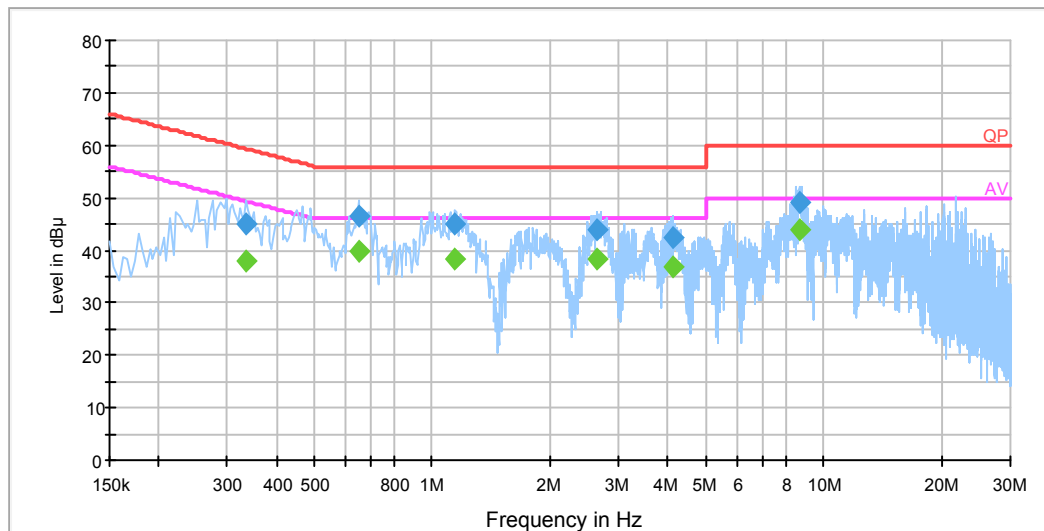


Frequency (MHz)	Corrected Amplitude (dBμV)	Correction Factor (dB)	Limit (dBμV)	Margin (dB)	Detector (PK/Ave./QP)
0.230000	44.2	19.5	62.4	18.3	QP
0.350000	42.0	19.5	59.0	17.0	QP
4.046000	36.8	19.7	56.0	19.2	QP
4.166000	36.4	19.7	56.0	19.6	QP
4.218000	34.3	19.7	56.0	21.7	QP
4.582000	34.0	19.7	56.0	22.0	QP
0.230000	37.9	19.5	52.4	14.6	Ave.
0.350000	35.6	19.5	49.0	13.4	Ave.
4.046000	29.8	19.7	46.0	16.2	Ave.
4.166000	27.8	19.7	46.0	18.2	Ave.
4.218000	25.7	19.7	46.0	20.3	Ave.
4.582000	26.7	19.7	46.0	19.3	Ave.

3) Adapter 3 power supply:

AC 230V/50 Hz, Line:

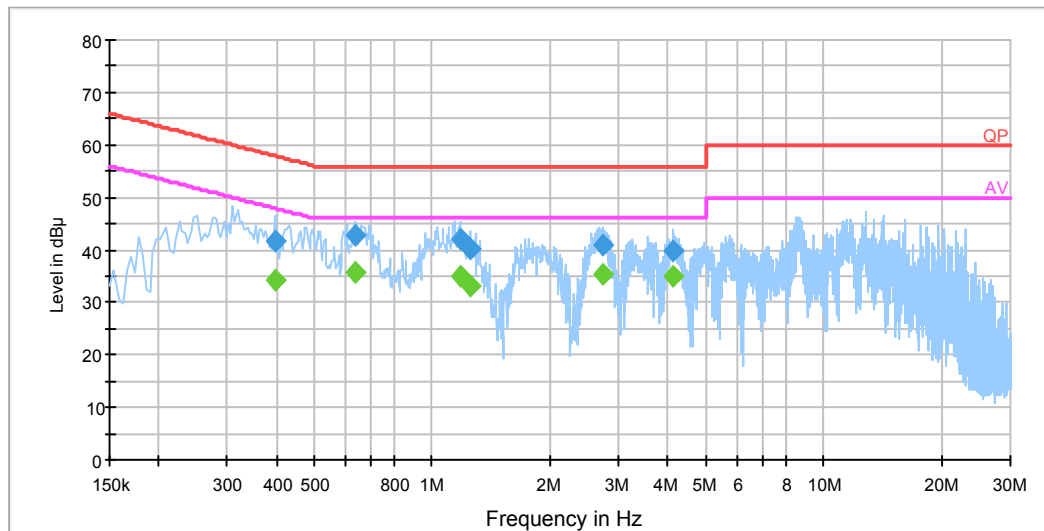
EMI Auto Test L



Frequency (MHz)	Corrected Amplitude (dBμV)	Correction Factor (dB)	Limit (dBμV)	Margin (dB)	Detector (PK/Ave./QP)
0.334000	45.1	19.5	59.4	14.3	QP
0.650000	46.6	19.5	56.0	9.4	QP
1.146000	45.1	19.5	56.0	10.9	QP
2.638000	44.1	19.5	56.0	11.9	QP
4.134000	42.5	19.6	56.0	13.5	QP
8.714000	49.0	19.7	60.0	11.0	QP
0.334000	37.8	19.5	49.4	11.6	Ave.
0.650000	39.6	19.5	46.0	6.4	Ave.
1.146000	38.2	19.5	46.0	7.8	Ave.
2.638000	38.4	19.5	46.0	7.6	Ave.
4.134000	36.9	19.6	46.0	9.1	Ave.
8.714000	43.8	19.7	50.0	6.2	Ave.

AC 230V/50 Hz, Neutral:

EMI Auto Test N

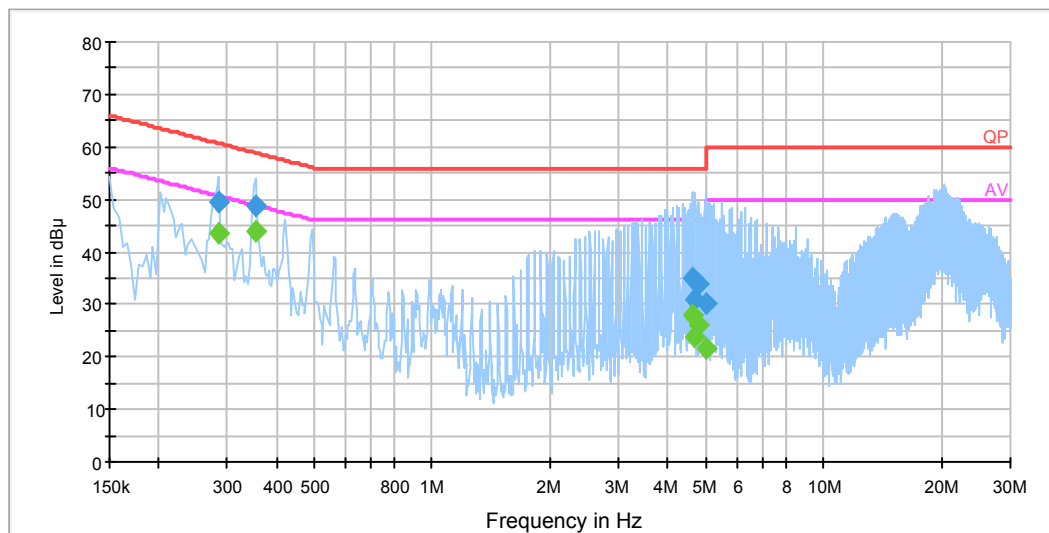


Frequency (MHz)	Corrected Amplitude (dBμV)	Correction Factor (dB)	Limit (dBμV)	Margin (dB)	Detector (PK/Ave./QP)
0.398000	41.6	19.5	57.9	16.3	QP
0.634000	42.9	19.5	56.0	13.1	QP
1.178000	42.1	19.5	56.0	13.9	QP
1.250000	40.0	19.5	56.0	16.0	QP
2.718000	40.8	19.6	56.0	15.2	QP
4.146000	39.8	19.7	56.0	16.2	QP
0.398000	34.3	19.5	47.9	13.6	Ave.
0.634000	35.6	19.5	46.0	10.4	Ave.
1.178000	34.8	19.5	46.0	11.2	Ave.
1.250000	33.0	19.5	46.0	13.0	Ave.
2.718000	35.4	19.6	46.0	10.6	Ave.
4.146000	35.1	19.7	46.0	10.9	Ave.

4) PoE power supply:

AC 230V/50 Hz, Line:

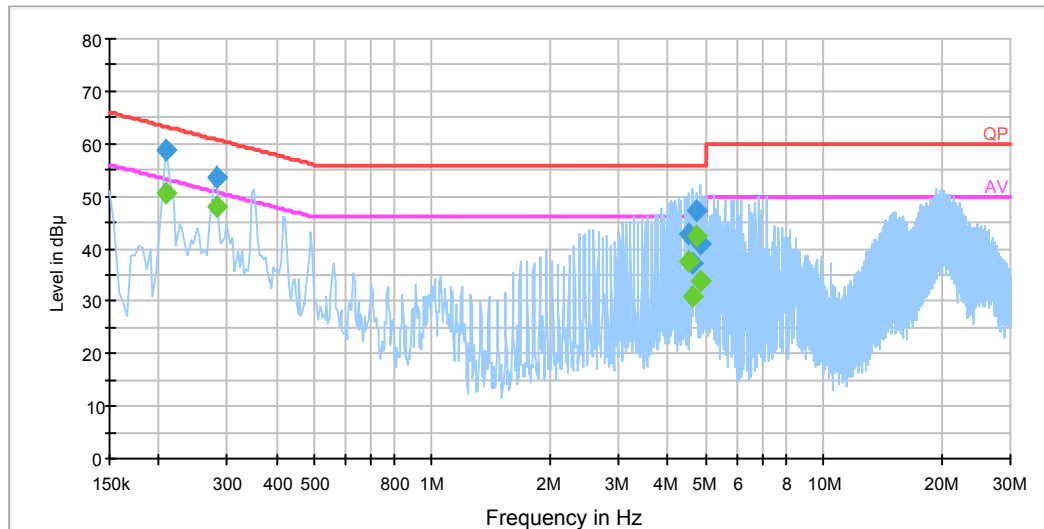
EMI Auto Test L



Frequency (MHz)	Corrected Amplitude (dBμV)	Correction Factor (dB)	Limit (dBμV)	Margin (dB)	Detector (PK/Ave./QP)
0.286000	49.4	19.5	60.6	11.3	QP
0.354000	48.8	19.5	58.9	10.1	QP
4.634000	34.8	19.6	56.0	21.2	QP
4.706000	30.7	19.6	56.0	25.3	QP
4.774000	33.8	19.6	56.0	22.2	QP
4.986000	30.2	19.6	56.0	25.8	QP
0.286000	43.5	19.5	50.6	7.1	Ave.
0.354000	43.7	19.5	48.9	5.1	Ave.
4.634000	27.8	19.6	46.0	18.2	Ave.
4.706000	23.7	19.6	46.0	22.3	Ave.
4.774000	26.1	19.6	46.0	19.9	Ave.
4.986000	21.5	19.6	46.0	24.5	Ave.

AC 230V/50 Hz, Neutral:

EMI Auto Test N

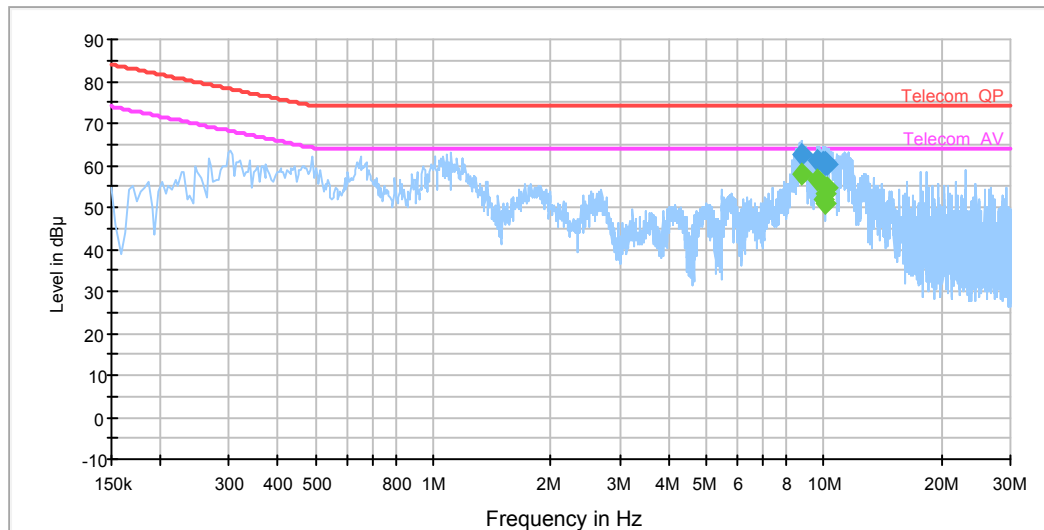


Frequency (MHz)	Corrected Amplitude (dBμV)	Correction Factor (dB)	Limit (dBμV)	Margin (dB)	Detector (PK/Ave./QP)
0.210000	58.7	19.5	63.2	4.5	QP
0.282000	53.6	19.5	60.8	7.1	QP
4.546000	42.8	19.7	56.0	13.2	QP
4.618000	37.2	19.7	56.0	18.8	QP
4.754000	47.3	19.7	56.0	8.7	QP
4.826000	41.1	19.7	56.0	14.9	QP
0.210000	50.4	19.5	53.2	2.8*	Ave.
0.282000	47.9	19.5	50.8	2.9*	Ave.
4.546000	37.8	19.7	46.0	8.2	Ave.
4.618000	30.8	19.7	46.0	15.2	Ave.
4.754000	42.5	19.7	46.0	3.5	Ave.
4.826000	33.9	19.7	46.0	12.1	Ave.

5) Telecommunication Port:

RJ45 Port:

CAT 5 Auto Test



Frequency (MHz)	Corrected Amplitude (dBμV)	Correction Factor (dB)	Limit (dBμV)	Margin (dB)	Detector (PK/Ave./QP)
8.770000	62.3	19.4	74.0	11.7	QP
9.658000	61.3	19.4	74.0	12.7	QP
9.998000	60.6	19.4	74.0	13.4	QP
10.026000	60.5	19.4	74.0	13.5	QP
10.098000	60.3	19.4	74.0	13.7	QP
10.194000	60.4	19.4	74.0	13.6	QP
8.770000	57.9	19.4	64.0	6.1	Ave.
9.658000	56.3	19.4	64.0	7.7	Ave.
9.998000	52.1	19.4	64.0	11.9	Ave.
10.026000	51.1	19.4	64.0	12.9	Ave.
10.098000	53.2	19.4	64.0	10.8	Ave.
10.194000	54.6	19.4	64.0	9.4	Ave.

Note:

- 1) Corrected Amplitude = Reading + Correction Factor
- 2) Correction Factor = LISN/ISN VDF (Voltage Division Factor) + Cable Loss + Pulse Limiter Attenuation
The corrected factor has been input into the transducer of the test software.
- 3) Margin = Limit – Corrected Amplitude
- 4) *within measurement uncertainty!

EN 55022 §6-RADIATED DISTURBANCE

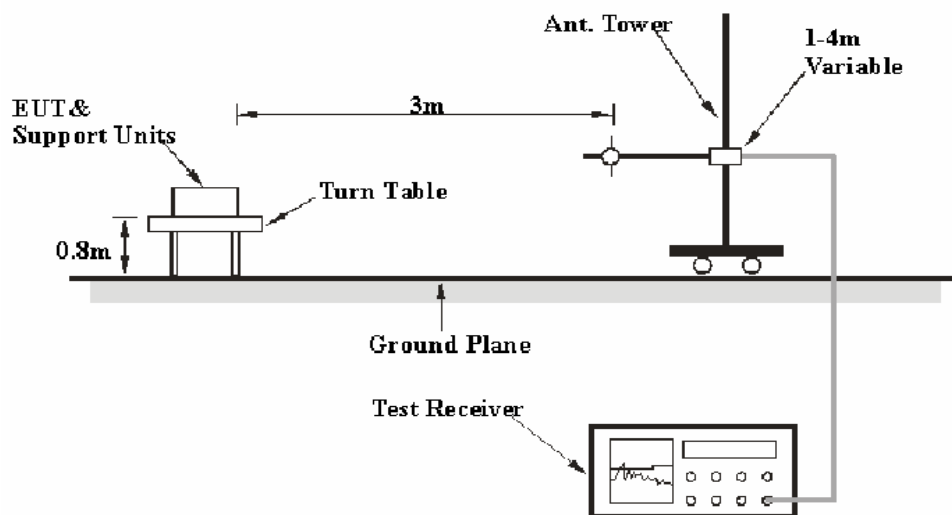
Measurement Uncertainty

All measurements involve certain levels of uncertainties, especially in field of EMC. The factors contributing to uncertainties are spectrum analyzer, cable loss, antenna factor calibration, antenna directivity, antenna factor variation with height, antenna phase center variation, antenna factor frequency interpolation, measurement distance variation, site imperfections, mismatch (average), and system repeatability.

Based on CISPR 16-4-2:2011, the expended combined standard uncertainty of radiation emissions at Bay Area Compliance Laboratories Corp. (Shenzhen) is shown in below table. And the uncertainty will not be taken into consideration for the test data recorded in the report

Frequency	Polarity	Measurement uncertainty
30MHz~200MHz	Horizontal	4.62 dB (k=2, 95% level of confidence)
	Vertical	4.54 dB (k=2, 95% level of confidence)
200MHz~1GHz	Horizontal	4.84 dB (k=2, 95% level of confidence)
	Vertical	5.91 dB (k=2, 95% level of confidence)
1 GHz~6 GHz	Horizontal / Vertical	4.68 dB (k=2, 95% level of confidence)
Above 6 GHz	Horizontal / Vertical	4.92 dB (k=2, 95% level of confidence)

Test System Setup



The radiated emission tests were performed in the 3 meters chamber A test site, using the setup accordance with the CISPR16-1-4:2012, CISPR 16-2-3:2010. The limit was specified in EN 55022 Class B.

The external I/O cables were draped along the test table and formed a bundle 30 to 40 cm long in the middle.

The spacing between the peripherals was 10 cm.

The adapter was connected to a 230 VAC/50 Hz power source.

EMI Test Receiver Setup

The system was investigated from 30 MHz to 2 GHz.

During the radiated emission test, the EMI test receiver was set with the following configurations:

Frequency Range	RBW	Video B/W	IF B/W	Detector
30 MHz – 1000 MHz	100 kHz	300 kHz	120 kHz	QP
Above 1 GHz	1 MHz	3 MHz	/	PK
	1 MHz	10 Hz	/	Ave.

Test Equipment List and Details

Manufacturer	Description	Model	Serial Number	Calibration Date	Calibration Due Date
HP	Amplifier	8447E	1937A01046	2012-11-24	2013-11-23
Rohde & Schwarz	EMI Test Receiver	ESCI	101122	2013-05-09	2014-05-09
Sunol Sciences	Broadband Antenna	JB1	A040904-2	2011-11-28	2014-11-27
Mini-Circuits	Amplifier	ZVA-213+	N/A	2012-11-24	2013-11-23
Sunol Sciences	Horn Antenna	DRH-118	A052304	2011-12-01	2014-11-30
Rohde & Schwarz	Signal Analyzer	FSIQ26	8386001028	2012-11-24	2013-11-23
R&S	Auto test Software	EMC32	V6.30	-	-

* **Statement of Traceability:** Bay Area Compliance Laboratories Corp. (Shenzhen) attests that all calibrations have been performed in accordance to requirements that traceable to National Primary Standards and International System of Units (SI).

Test Procedure

During the radiated emissions, the adapter was connected to the AC floor outlet.

Maximizing procedure was performed on the highest emissions to ensure that the EUT complied with all installation combinations.

Data was recorded in Quasi-peak detection mode from 30 MHz to 1 GHz, peak and average detection modes for frequencies above 1 GHz.

Corrected Amplitude & Margin Calculation

The Corrected Amplitude is calculated by adding the Antenna Factor and Cable Loss, and subtracting the Amplifier Gain from the Meter Reading. The basic equation is as follows:

$$\text{Corrected Amplitude} = \text{Meter Reading} + \text{Antenna Factor} + \text{Cable Loss} - \text{Amplifier Gain}$$

The “**Margin**” column of the following data tables indicates the degree of compliance with the applicable limit. For example, a margin of 7 dB means the emission is 7 dB below the limit for Class B. The equation for margin calculation is as follows:

$$\text{Margin} = \text{Limit} - \text{Corrected Amplitude.}$$

Test Results Summary

According to the data in the following table, with the worst margin reading of:

3.3 dB at 375.003200 MHz in the Vertical polarization (adapter 3 power supply)

Refer to CISPR16-4-2:2011 and CISPR 16-4-1:2009, the measured level is in compliance with the limit if

$$L_m + U_{(Lm)} \leq L_{lim} + U_{cispr}$$

in BACL, $U_{(Lm)}$ is less than U_{cispr} , if L_m is less than L_{lim} , it implies that the EUT complies with the limit.

Test Data

Environmental Conditions

Temperature:	25 °C
Relative Humidity:	56 %
ATM Pressure:	100.0 kPa

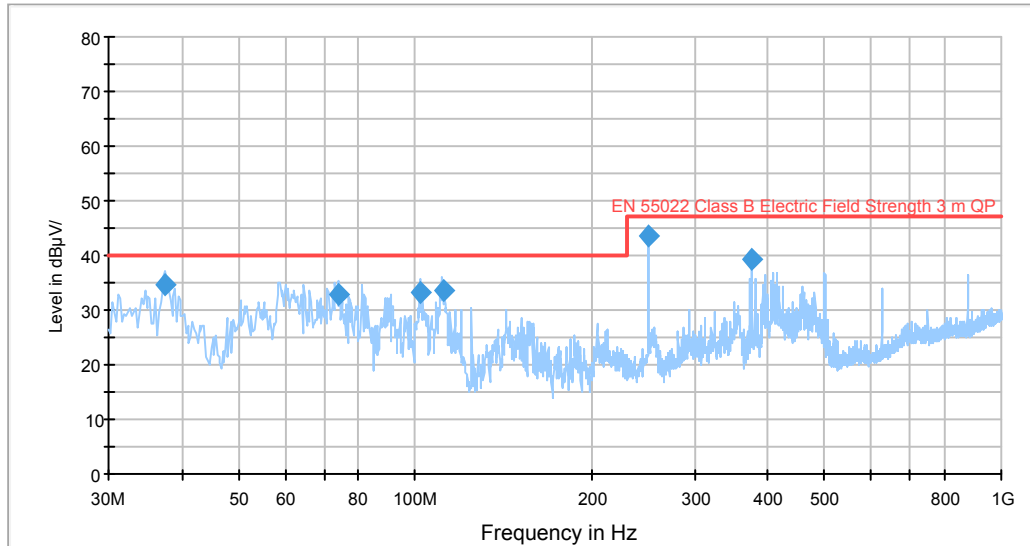
The testing was performed by Joson Xiao on 2013-06-25.

Test Mode: Talking

1) Adapter 1 power supply:

Below 1 GHz:

Auto Test(EN55022 Class B)



Frequency (MHz)	Corrected Amplitude (dBμV/m)	Antenna height (cm)	Antenna Polarity	Turntable position (degree)	Correction Factor (dB/m)	Limit (dBμV/m)	Margin (dB)
249.999750	43.6	100.0	H	164.0	-13.5	47.0	3.4
37.383750	34.8	122.0	V	179.0	-10.4	40.0	5.2
111.556500	33.6	100.0	V	279.0	-13.2	40.0	6.4
101.880250	33.2	100.0	V	316.0	-14.4	40.0	6.8
73.919000	32.9	100.0	V	150.0	-18.2	40.0	7.1
375.075500	39.2	372.0	H	3.0	-10.5	47.0	7.8

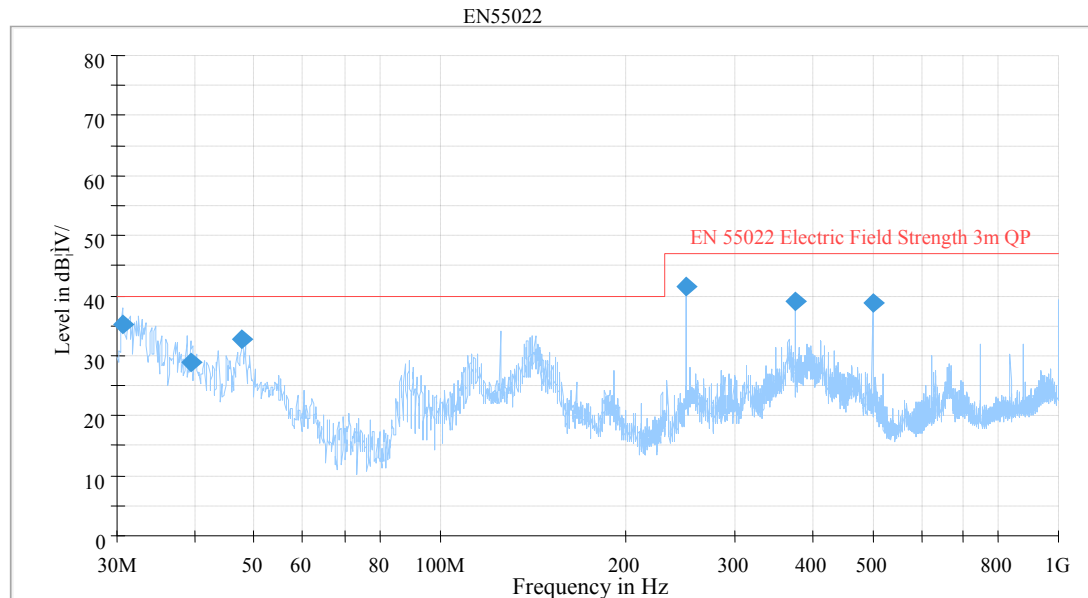
Above 1 GHz:

Frequency (MHz)	S.A Reading (dBμV/m)	Detector (PK /Ave.)	Direction Degree	Antenna Height (m)	Polarity (H/V)	Antenna Factor (dB/m)	Cable loss (dB)	Amplifier Gain (dB)	Corrected Amplitude (dBμV/m)	EN55022	
										Limit (dBμV/m)	Margin (dB)
1250.5	37.01	Ave.	330	1.0	H	24.5	2.06	26.55	37.02	50	12.98
1200.4	36.30	Ave.	330	1.0	V	24.3	2.03	26.53	36.10	50	13.90
1250.5	43.36	PK	330	1.0	H	24.5	2.06	26.55	43.37	70	26.63
1200.4	43.44	PK	330	1.0	V	24.3	2.03	26.53	43.24	70	26.76

Note: The data which below the limit 20 dB was not recorded.

2) Adapter 2 power supply:

Below 1 GHz:



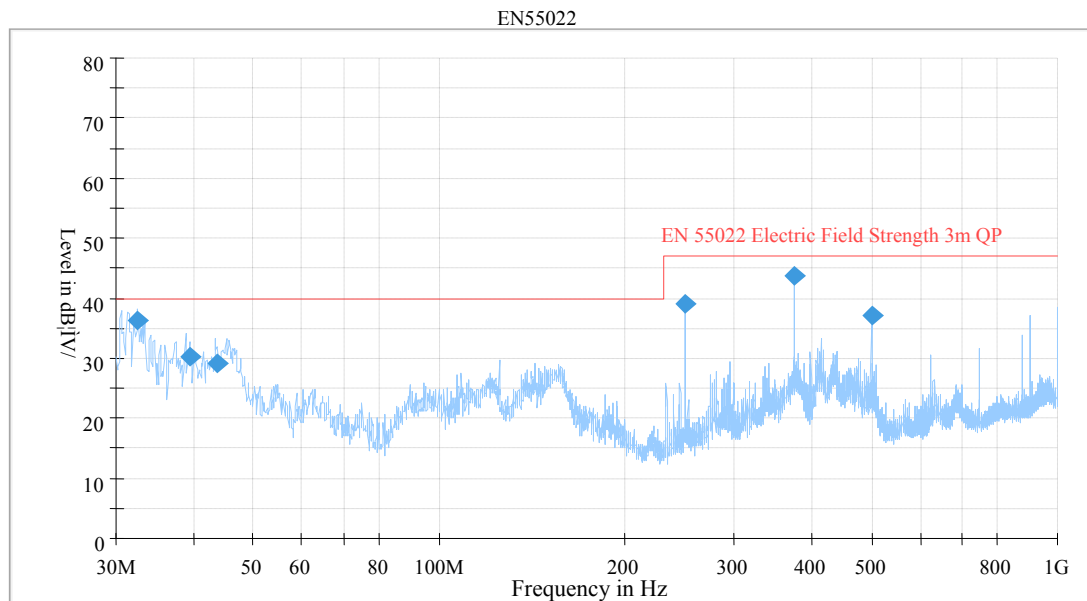
Frequency (MHz)	Corrected Amplitude (dB μ V/m)	Antenna height (cm)	Antenna Polarity	Turntable position (degree)	Correction Factor (dB/m)	Limit (dB μ V/m)	Margin (dB)
30.636400	35.2	100.0	V	174.0	-7.2	40.0	4.8
39.514000	28.9	106.0	V	150.0	-14.0	40.0	11.1
47.788000	32.6	100.0	V	259.0	-19.2	40.0	7.4
250.005600	41.6	118.0	H	24.0	-15.8	47.0	5.4
375.077500	39.2	166.0	H	117.0	-12.9	47.0	7.8
500.006900	38.8	118.0	H	331.0	-10.1	47.0	8.2

Above 1 GHz:

Frequency (MHz)	Receiver		Turntable Degree	Rx Antenna		Correction Factor (dB/m)	Corrected Amplitude (dB μ V/m)	EN 55022	
	Reading (dB μ V)	Detector (PK/QP/Ave.)		Height (m)	Polar (H/V)			Limit (dB μ V/m)	Margin (dB)
1671.3	46.61	PK	195	1.3	H	2.24	48.85	70	21.15
1671.3	38.88	Ave.	195	1.3	H	2.24	41.12	50	8.88
1737.5	47.72	PK	40	1.4	H	2.32	50.04	70	19.96
1737.5	43.77	Ave.	40	1.4	H	2.32	46.09	50	3.91*
1671.3	47.14	PK	340	1.8	V	2.24	49.38	70	20.62
1671.3	40.02	Ave.	340	1.8	V	2.24	42.26	50	7.74
1737.5	49.85	PK	112	1.8	V	2.32	52.17	70	17.83
1737.5	44.46	Ave.	112	1.8	V	2.32	46.78	50	3.22*

3) Adapter 3 power supply:

Below 1 GHz:



Frequency (MHz)	Corrected Amplitude (dBµV/m)	Antenna height (cm)	Antenna Polarity	Turntable position (degree)	Correction Factor (dB/m)	Limit (dBµV/m)	Margin (dB)
32.583600	36.4	100.0	V	190.0	-8.8	40.0	3.6*
39.539800	30.1	100.0	V	90.0	-14.0	40.0	9.9
43.773900	29.1	100.0	V	76.0	-17.0	40.0	10.9
250.015950	39.1	141.0	H	51.0	-15.8	47.0	7.9
375.003200	43.7	100.0	H	8.0	-12.9	47.0	3.3*
500.010300	37.2	107.0	V	131.0	-10.1	47.0	9.8

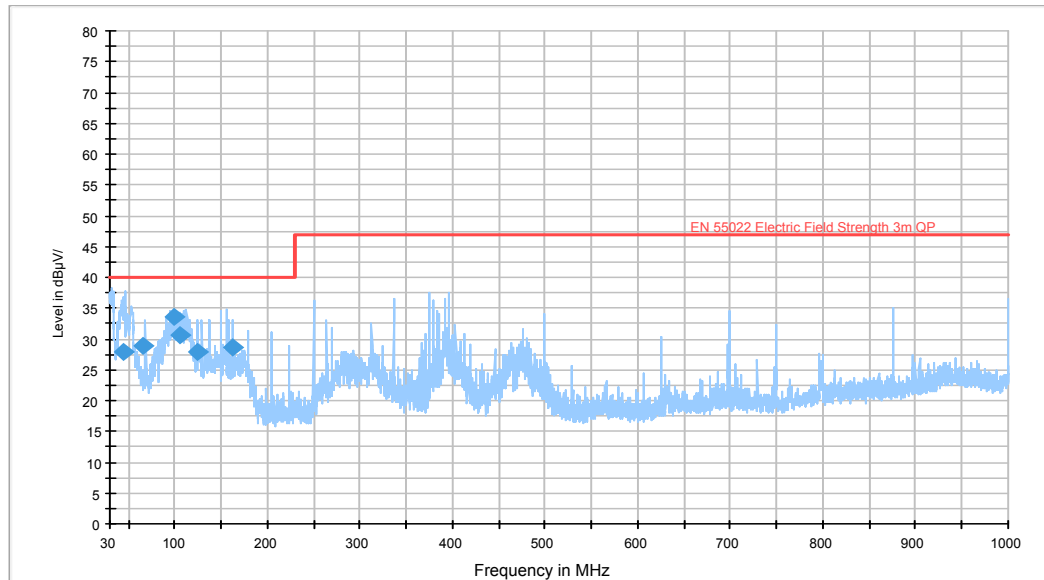
Above 1 GHz:

Frequency (MHz)	Receiver		Turntable Degree	Rx Antenna		Correction Factor (dB/m)	Corrected Amplitude (dBµV/m)	EN 55022	
	Reading (dBµV)	Detector (PK/QP/Ave.)		Height (m)	Polar (H/V)			Limit (dBµV/m)	Margin (dB)
1667.3	46.88	PK	213	2.2	H	2.24	49.12	70	20.88
1667.3	37.57	Ave.	213	2.2	H	2.24	39.81	50	10.19
1813.6	43.76	PK	159	1.8	H	2.63	46.39	70	23.61
1813.6	34.86	Ave.	159	1.8	H	2.63	37.49	50	12.51
1667.3	49.70	PK	301	2.0	V	2.24	51.94	70	18.06
1667.3	40.39	Ave.	301	2.0	V	2.24	42.63	50	7.37
1813.6	48.14	PK	112	2.2	V	2.63	50.77	70	19.23
1813.6	39.50	Ave.	112	2.2	V	2.63	42.13	50	7.87

3) PoE power supply:

Below 1 GHz:

EN55022



Frequency (MHz)	Corrected Amplitude (dBμV/m)	Antenna height (cm)	Antenna Polarity	Turntable position (degree)	Correction Factor (dB/m)	Limit (dBμV/m)	Margin (dB)
44.430050	27.9	281.0	H	38.0	-17.4	40.0	12.1
66.253050	29.0	401.0	H	170.0	-20.6	40.0	11.0
100.049100	33.7	177.0	H	105.0	-17.4	40.0	6.3
106.711600	30.5	99.0	V	106.0	-15.6	40.0	9.5
124.985300	28.0	309.0	H	225.0	-13.4	40.0	12.0
161.741650	28.6	225.0	H	74.0	-15.4	40.0	11.4

Above 1 GHz:

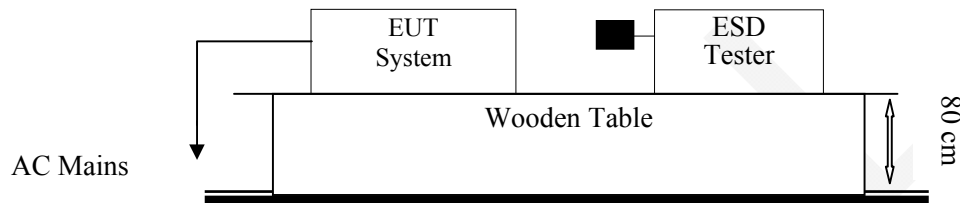
Frequency (MHz)	Receiver		Turntable Degree	Rx Antenna		Correction Factor (dB/m)	Corrected Amplitude (dBμV/m)	EN 55022	
	Reading (dBμV)	Detector (PK/QP/Ave.)		Height (m)	Polar (H/V)			Limit (dBμV/m)	Margin (dB)
1000.0	49.11	PK	72	1.7	H	-1.20	47.91	70	22.09
1000.0	39.95	Ave.	72	1.7	H	-1.20	38.75	50	11.25
1501.0	45.06	PK	240	1.9	H	1.15	46.21	70	23.79
1501.0	37.02	Ave.	240	1.9	H	1.15	38.17	50	11.83
1000.0	50.62	PK	86	1.6	V	-1.20	49.42	70	20.58
1000.0	43.38	Ave.	86	1.6	V	-1.20	42.18	50	7.82
1501.0	47.79	PK	216	1.4	V	1.15	48.94	70	21.06
1501.0	40.22	Ave.	216	1.4	V	1.15	41.37	50	8.63

*within measurement uncertainty!

EN 55024 §4.2.1-ELECTROSTATIC DISCHARGES (IEC 61000-4-2)**Test Equipment**

Manufacturer	Description	Model	Serial Number	Calibration Date	Calibration Due Date
EM Test	ESD Tester	Dito	302105	2010-10-27	2011-10-26

* **Statement of Traceability:** Bay Area Compliance Laboratories Corp. (Shenzhen) attests that all calibrations have been performed in accordance to requirements that traceable to National Primary Standards and International System of Units (SI).

Test System Setup

Remark: ■ is the tip of the electrode

IEC 61000-4-2 specifies that a tabletop EUT shall be placed on a non-conducting table which is 80 centimeters above a ground reference plane and that floor mounted equipment shall be placed on a insulating support approximately 10 centimeters above a ground plane. During the tests, the EUT is positioned over a ground reference plane in conformance with this requirement.

For tabletop equipment, a 1.5 by 1.0-meter metal sheet (HCP) is placed on the table and connected to the ground plane via a metal strap with two 470 k Ohms resistors in series. The EUT and attached cables are isolated from this metal sheet by 0.5-millimeter thick insulating material. A Vertical Coupling Plane (VCP) grounded on the ground plane through the same configuration as in the HCP is used.

Test Standard

EN 55024:2010 (IEC 61000-4-2:2008)

Test level 3 for Air Discharge at ± 8 kV

Test level 2 for Contact Discharge at ± 4 kV

Test Level

Level	Test Voltage Contact Discharge ($\pm$ kV)	Test Voltage Air Discharge ($\pm$ kV)
1.	2	2
2.	4	4
3.	6	8
4.	8	15
X.	Special	Special

Performance criterion: B

Test Procedure

Air Discharge:

This test is done on a non-conductive surface. The round discharge tip of the discharge electrode shall be approached as fast as possible to touch the EUT. After each discharge, the discharge electrode shall be removed from the EUT. The generator is then re-triggered for a new single discharge and repeated 10 times for each pre-selected test point. This procedure shall be repeated until all the air discharge completed.

Contact Discharge:

All the procedure shall be same as Section 8.3.1 of IEC 61000-4-2, except that the tip of the discharge electrode shall touch the EUT before the discharge switch is operated.

Indirect discharge for horizontal coupling plane

At least 20 single discharges shall be applied to the horizontal coupling plane, at points on each side of the EUT. The discharge electrode positions vertically at a distance of 0.1 m from the EUT and with the discharge electrode touching the coupling plane.

Indirect discharge for vertical coupling plane

At least 20 single discharges shall be applied to the center of one vertical edge of the coupling plane. The coupling plane, of dimensions 0.5m × 0.5m, is placed parallel to, and positioned at a distance of 0.1m from the EUT. Discharges shall be applied to the coupling plane, with this plane in sufficient different positions that the four faces of the EUT are completely illuminated.

Test Data and Setup Photo

Environmental Conditions

Temperature:	25 °C
Relative Humidity:	50 %
ATM Pressure:	101.0 kPa

The testing was performed by Lebron Wang on 2011-09-15.

Test Mode: Talking

1) Adapter power supply:

Table 1: Electrostatic Discharge Immunity (Air Discharge)

IEC 61000-4-2 Test Points Location	Test Levels							
	-2 kV	+2 kV	-4 kV	+4 kV	-8 kV	+8 kV	-15 kV	+15 kV
LCD (10 points)	A	A	A	A	A	A	/	/
Surface Crack (8 points)	A	A	A	A	A	A	/	/
Key (49 points)	A	A	A	A	A	A	/	/
Speaker (5 points)	A	A	A	A	A	A	/	/
RJ11 Port (3 points)	A	A	A	A	A	A	/	/
RJ45 Port (2 points)	A	A	A	A	A	A	/	/
Microphone (1 point)	A	A	A	A	A	A	/	/

Table 2: Electrostatic Discharge Immunity (Direct Contact)

IEC 61000-4-2 Test Points Location	Test Levels							
	-2 kV	+2 kV	-4 kV	+4 kV	-6 kV	+6 kV	-8 kV	+8 kV
/	/	/	/	/	/	/	/	/

Table 3: Electrostatic Discharge Immunity (Indirect Contact HCP)

IEC 61000-4-2 Test Points Location	Test Levels							
	-2 kV	+2 kV	-4 kV	+4 kV	-6 kV	+6 kV	-8 kV	+8 kV
Front Side	A	A	A	A	/	/	/	/
Back Side	A	A	A	A	/	/	/	/
Left Side	A	A	A	A	/	/	/	/
Right Side	A	A	A	A	/	/	/	/

Table 4: Electrostatic Discharge Immunity (Indirect Contact VCP)

IEC 61000-4-2 Test Points Location	Test Levels							
	-2 kV	+2 kV	-4 kV	+4 kV	-6 kV	+6 kV	-8 kV	+8 kV
Front Side	A	A	A	A	/	/	/	/
Back Side	A	A	A	A	/	/	/	/
Left Side	A	A	A	A	/	/	/	/
Right Side	A	A	A	A	/	/	/	/

Air Discharge



Indirect Contact



Test Setup Photos

2) PoE power supply:

Table 1: Electrostatic Discharge Immunity (Air Discharge)

IEC 61000-4-2 Test Points Location	Test Levels							
	-2 kV	+2 kV	-4 kV	+4 kV	-8 kV	+8 kV	-15 kV	+15 kV
LCD (10 points)	A	A	A	A	A	A	/	/
Surface Crack (8 points)	A	A	A	A	A	A	/	/
Key (49 points)	A	A	A	A	A	A	/	/
Speaker (5 points)	A	A	A	A	A	A	/	/
RJ11 Port (3 points)	A	A	A	A	A	A	/	/
RJ45 Port (2 points)	A	A	A	A	A	A	/	/
Microphone (1 point)	A	A	A	A	A	A	/	/

Table 2: Electrostatic Discharge Immunity (Direct Contact)

IEC 61000-4-2 Test Points Location	Test Levels							
	-2 kV	+2 kV	-4 kV	+4 kV	-6 kV	+6 kV	-8 kV	+8 kV
/	/	/	/	/	/	/	/	/

Table 3: Electrostatic Discharge Immunity (Indirect Contact HCP)

IEC 61000-4-2 Test Points Location	Test Levels							
	-2 kV	+2 kV	-4 kV	+4 kV	-6 kV	+6 kV	-8 kV	+8 kV
Front Side	A	A	A	A	/	/	/	/
Back Side	A	A	A	A	/	/	/	/
Left Side	A	A	A	A	/	/	/	/
Right Side	A	A	A	A	/	/	/	/

Table 4: Electrostatic Discharge Immunity (Indirect Contact VCP)

IEC 61000-4-2 Test Points Location	Test Levels							
	-2 kV	+2 kV	-4 kV	+4 kV	-6 kV	+6 kV	-8 kV	+8 kV
Front Side	A	A	A	A	/	/	/	/
Back Side	A	A	A	A	/	/	/	/
Left Side	A	A	A	A	/	/	/	/
Right Side	A	A	A	A	/	/	/	/

Air Discharge



Indirect Contact

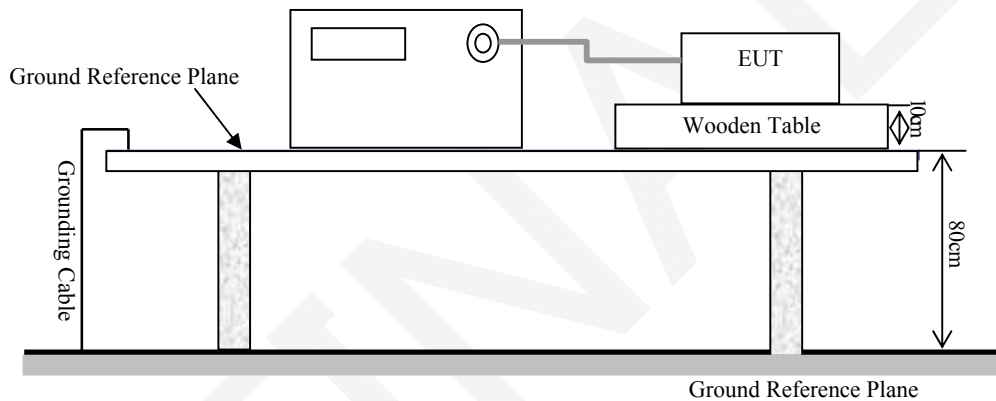


Test Setup Photos

EN 55024 §4.2.2-ELECTRICAL FAST TRANSIENTS (IEC 61000-4-4)**Test Equipment**

Manufacturer	Description	Model	Serial Number	Calibration Date	Calibration Due Date
EM Test	Ultra Compact Generator	UCS500-N5	V0939105172	2011-07-04	2012-07-03
EM Test	Auto-transformer	MV2616	V0939105173	2011-07-04	2012-07-03
EM Test	EFT Clamp	N/A	300886	2011-07-04	2012-07-03

* **Statement of Traceability:** Bay Area Compliance Laboratories Corp. (Shenzhen) attests that all calibrations have been performed in accordance to requirements that traceable to National Primary Standards and International System of Units (SI).

Test System Setup**Test Standard**

EN 55024:2010 (IEC 61000-4-4:2004)

AC mains: Test level 2 at 1 kV

Signal port: Test level 2 at 0.5 kV

Test Level

Open Circuit Output Test Voltage $\pm 10\%$		
Level	On Power Supply Lines	On I/O (Input/Output) Signal data and control lines
1	0.5 kV	0.25 kV
2	1 kV	0.5 kV
3	2 kV	1 kV
4	4 kV	2 kV
X	Special	Special

Performance Criterion: B

Test Procedure

The EUT was arranged for Power Line Coupling and for I/O Line Coupling through a capacitive clamp, where applicable. (Note: The I/O coupling test using a capacitive clamp is performed on the I/O interface cables that are longer in length than 3 meters.) A metal ground plane 2.4 meter by 2.0 meter was placed between the floor and the table and is connected to the earth by a 2.0 meter ground rod. The ground rod is connected to the test facility's electrical earth.

Test Data and Setup Photo

Environmental Conditions

Temperature:	25 °C
Relative Humidity:	50 %
ATM Pressure:	101.0 kPa

The testing was performed by Lebron Wang on 2011-09-15.

.Test Mode: Talking

1) Adapter power supply:

IEC 61000-4-4 Test Points		Test Levels (kV)							
		+0.5	-0.5	+1.0	-1.0	+2.0	-2.0	+4.0	-4.0
AC mains power input ports	L1	A	A	A	A	/	/	/	/
	L2	A	A	A	A	/	/	/	/
	Earth	/	/	/	/	/	/	/	/
	L1+L2	A	A	A	A	/	/	/	/
	L1 + Earth	/	/	/	/	/	/	/	/
	L2 + Earth	/	/	/	/	/	/	/	/
	L1+L2+Earth	/	/	/	/	/	/	/	/
Signal ports	RJ45	A	A	/	/	/	/	/	/

2) PoE power supply:

IEC 61000-4-4 Test Points		Test Levels (kV)							
		+0.5	-0.5	+1.0	-1.0	+2.0	-2.0	+4.0	-4.0
AC mains power input ports	L1	A	A	A	A	/	/	/	/
	L2	A	A	A	A	/	/	/	/
	Earth	A	A	A	A	/	/	/	/
	L1+L2	A	A	A	A	/	/	/	/
	L1 + Earth	A	A	A	A	/	/	/	/
	L2 + Earth	A	A	A	A	/	/	/	/
	L1+L2+Earth	A	A	A	A	/	/	/	/
Signal ports	RJ45	A	A	/	/	/	/	/	/

1) Adapter power supply

AC Mains Port



RJ45 port



2) PoE power supply

AC Mains Port



RJ45 port

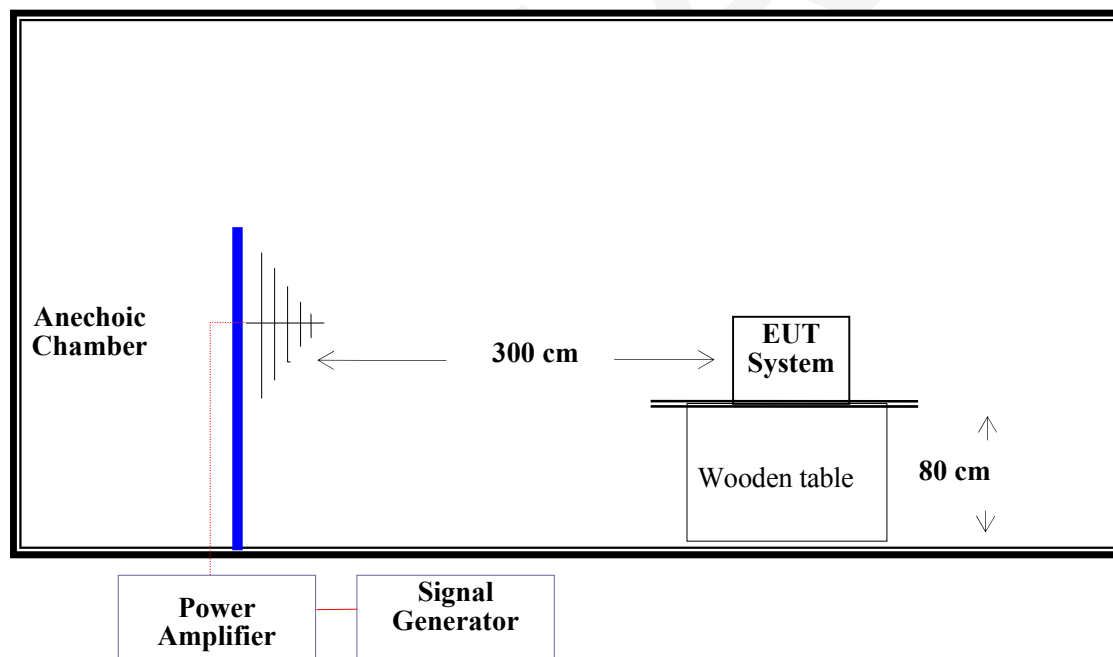


Test Setup Photos

EN 55024 §4.2.3.1-CONTINUOUS RADIATED DISTURBANCES (IEC 61000-4-3)**Test Equipment**

Manufacturer	Description	Model	Serial Number	Calibration Date	Calibration Due Date
Amplifier Research	Amplifier	200W1000/M2	15893	2011-01-14	2012-01-14
Amplifier Research	Field Meter	FM5004	302149	2011-03-31	2012-03-30
ETS-LINDGREN	Sensor	HI-6005	N/A	2011-03-31	2012-03-30
HP	Signal Generator	HP8657A	2849U00982	2010-10-28	2011-10-27
Amplifier Research	Biconilog Antenna	AT1080	301902	N/A	N/A

* **Statement of Traceability:** Bay Area Compliance Laboratories Corp. (Shenzhen) attests that all calibrations have been performed in accordance to requirements that traceable to National Primary Standards and International System of Units (SI).

Test System Setup

Test Standard

EN 55024:2010 (IEC 61000-4-3: 2006 + A1:2007 + A2:2010)
Test level 2 at 3V / m

Test Level

Level	Field Strength V/m
1.	1
2.	3
3.	10
X.	Special

Performance Criterion: A**Test Procedure**

The EUT and its simulators are placed on a turn table which is 0.8 meter above the ground. The EUT is set 3 meters away from the transmitting antenna which is mounted on an antenna tower. Both horizontal and vertical polarizations of the antenna are set on test. Each of the four sides of EUT must be faced this transmitting antenna and measured individually.

In order to judge the EUT performance, a CCD camera is used to monitor the EUT.

All the scanning conditions are as follows:

Condition of Test	Remarks
1. Field Strength	3 V/m (Test level 2)
2. Radiated Signal	AM 80%, 1 kHz Modulation
3. Scanning Frequency	80 – 1000 MHz
4. Sweeping time of radiated	0.0015decade/s
5. Dwell Time	1Sec.

Test Data and Setup Photo**Environmental Conditions**

Temperature:	25 °C
Relative Humidity:	50 %
ATM Pressure:	101.0 kPa

The testing was performed by Lebron Wang on 2011-09-13.

Test Mode: Talking

1) Adapter power supply:

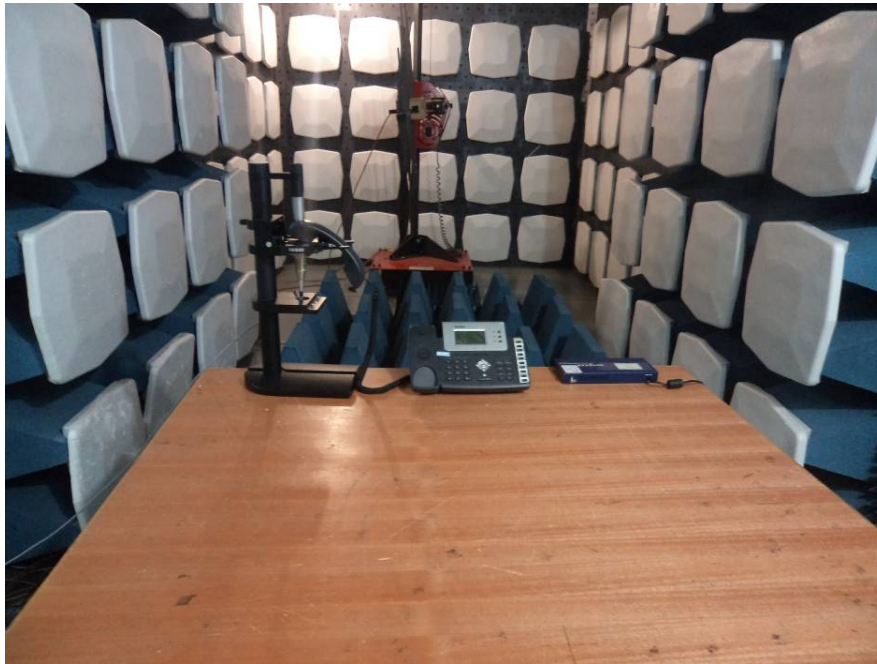
Frequency Range (MHz)	Front Side (3 V/m)		Rear Side (3 V/m)		Left Side (3 V/m)		Right Side (3 V/m)	
	VERT	HORI	VERT	HORI	VERT	HORI	VERT	HORI
80-1000	A	A	A	A	A	A	A	A



Test Setup Photo

2) PoE power supply:

Frequency Range (MHz)	Front Side (3 V/m)		Rear Side (3 V/m)		Left Side (3 V/m)		Right Side (3 V/m)	
	VERT	HORI	VERT	HORI	VERT	HORI	VERT	HORI
80-1000	A	A	A	A	A	A	A	A



Test Setup Photo

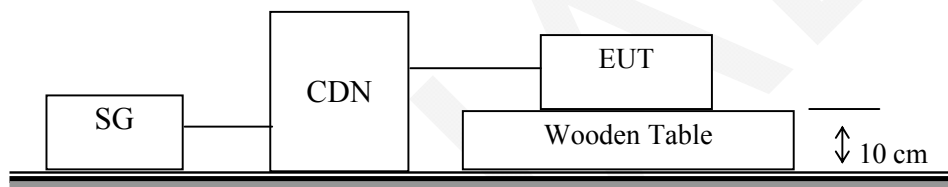
EN 55024 §4.2.3.2-CONTINUOUS CONDUCTED DISTURBANCES (IEC 61000-4-6)

Test Equipment

Manufacturer	Description	Model	Serial Number	Calibration Date	Calibration Due Date
EM Test	CDN	M3	1201-05	2011-03-09	2012-03-08
EM Test	C/S Tester	CWS500	303277	2010-11-03	2011-11-02
EM Test	Attenuator	6dB	303282	2010-11-15	2011-11-14

* **Statement of Traceability:** Bay Area Compliance Laboratories Corp. (Shenzhen) attests that all calibrations have been performed in accordance to requirements that traceable to National Primary Standards and International System of Units (SI).

Test Setup



Test Standard

EN 55024:2010 (IEC 61000-4-6:2008)
Test level 2 at 3 V (r.m.s.), 0.15 MHz ~ 80 MHz,

Test Level

Level	Voltage Level (r.m.s.) (V)
1	1
2	3
3	10
X	Special

Performance Criterion: A

Test Procedure

- 1) Let the EUT work in test mode and test it.
- 2) The EUT are placed on an insulating support 0.1 m high above a ground reference plane. CDN (coupling and decoupling device) is placed on the ground plane about 0.3 m from EUT. Cables between CDN and EUT are as short as possible, and their height above the ground reference plane shall be between 30 and 50 mm (where possible).
- 3) The disturbance signal described below is injected to EUT through CDN.
- 4) The EUT operates within its operational mode(s) under intended climatic conditions after power on.
- 5) The frequency range is swept from 150 kHz to 80 MHz using 3V signal level, and with the disturbance signal 80% amplitude modulated with a 1 kHz sine wave.
- 6) The rate of sweep shall not exceed 1.5×10^{-3} decades/s. Where the frequency is swept incrementally, the step size shall not exceed 1% of the start and thereafter 1% of the preceding frequency value.
- 7) Recording the EUT operating situation during compliance testing and decide the EUT immunity criterion.

Test Data and Setup Photo

Environmental Conditions

Temperature:	25 °C
Relative Humidity:	50 %
ATM Pressure:	101.0 kPa

The testing was performed by Lebron Wang on 2011-09-13.

Test Mode: Talking

- 1) Adapter power supply:

Table 1: AC mains power input port

Modulation: Amplitude 80%, 1 kHz sine wave

Test level: 3V r.m.s.

Level	Voltage Level (r.m.s.) U_0	Pass	Fail
1	1	/	/
2	3	A	/
3	10	/	/
X	Special	/	/

Table 2: RJ45 port

Modulation: Amplitude 80%, 1 kHz sine wave

Test level: 3V r.m.s.

Level	Voltage Level (r.m.s.) U_0	Pass	Fail
1	1	/	/
2	3	A	/
3	10	/	/
X	Special	/	/

AC Mains



RJ45 Port



Test Setup Photos

2) PoE power supply:

Table 1: AC mains power input port

Modulation: Amplitude 80%, 1 kHz sine wave

Test level: 3V r.m.s.

Level	Voltage Level (r.m.s.) U_0	Pass	Fail
1	1	/	/
2	3	A	/
3	10	/	/
X	Special	/	/

Table 2: RJ45 port

Modulation: Amplitude 80%, 1 kHz sine wave

Test level: 3V r.m.s.

Level	Voltage Level (r.m.s.) U_0	Pass	Fail
1	1	/	/
2	3	A	/
3	10	/	/
X	Special	/	/

AC Mains



RJ45 Port

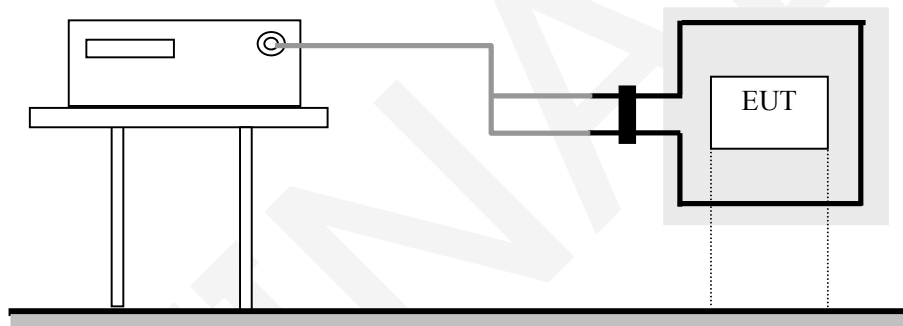


Test Setup Photos

EN 55024 §4.2.4-POWER FREQUENCY MAGNETIC FIELDS (IEC 61000-4-8)**Test Equipment**

Manufacturer	Description	Model	Serial Number	Calibration Date	Calibration Due Date
EM Test	Ultra Compact Generator	UCS500-N5	V0939105172	2011-07-04	2012-07-03
EM Test	Auto-transformer	MV2616	V0939105173	2011-07-04	2012-07-03
EM Test	Current Transformer	MC2630	0309-59	2011-03-09	2012-03-08
EM Test	Loop Antenna	MS100	0809-05	2011-03-09	2012-03-08

* **Statement of Traceability:** Bay Area Compliance Laboratories Corp. (Shenzhen) attests that all calibrations have been performed in accordance to requirements that traceable to National Primary Standards and International System of Units (SI).

Test Setup**Test Standard**

EN 55024:2010 (IEC 61000-4-8:2009)
Test level 1 at 1A/m

Test Level

Level	Magnetic Field Strength A/m
1	1
2	3
3	10
4	30
5	100
X.	Special

Performance criterion: A

Test Procedure

The EUT shall be subjected to the test magnetic field by using the induction coil of standard dimensions (1 m*1 m). The induction coil shall then be rotated by 90° in order to expose the EUT to the test field with different orientations.

Test Data and Setup Photo

Environmental Conditions

Temperature:	25 °C
Relative Humidity:	50 %
ATM Pressure:	101.0 kPa

The testing was performed by Lebron Wang on 2011-09-15.

Test Mode: Talking

1) Adapter power supply:

Level	Magnetic Field Strength A/m	X (Horizontal)	Y (Vertical)	Z (Special)
1	1	A	A	A
2	3	/	/	/
3	10	/	/	/
4	30	/	/	/
5	100	/	/	/
X	Special	/	/	/

2) PoE power supply:

Level	Magnetic Field Strength A/m	X (Horizontal)	Y (Vertical)	Z (Special)
1	1	A	A	A
2	3	/	/	/
3	10	/	/	/
4	30	/	/	/
5	100	/	/	/
X	Special	/	/	/

Adapter power supply:



PoE power supply:

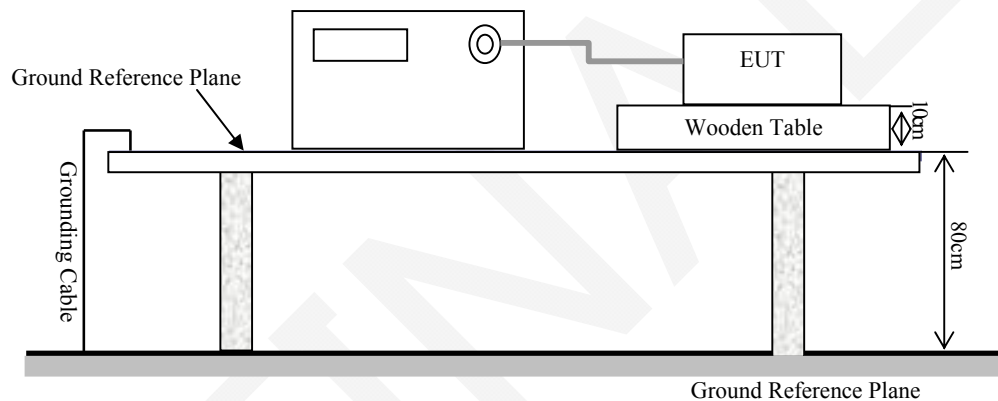


Test Setup Photos

EN 55024 §4.2.5-SURGES (IEC 61000-4-5)**Test Equipment**

Manufacturer	Description	Model	Serial Number	Calibration Date	Calibration Due Date
EM Test	Ultra Compact Generator	UCS500-N5	V0939105172	2011-07-04	2012-07-03
EM Test	Auto-transformer	MV2616	V0939105173	2011-07-04	2012-07-03
EM Test	CDN	CNV 504S1	V0939105175	2011-07-04	2012-07-03

* **Statement of Traceability:** Bay Area Compliance Laboratories Corp. (Shenzhen) attests that all calibrations have been performed in accordance to requirements that traceable to National Primary Standards and International System of Units (SI).

Test System Setup**Test Standard**

EN 55024:2010 (IEC 61000-4-5:2005)

AC Mains: L-N: Test level 2 at 1 kV

L-PE, N-PE: Test level 1 at 0.5 kV

Signal port: Test level 2 at 1 kV

Test Level

Level	Open Circuit Output Test Voltage $\pm 10\%$
1	0.5 kV
2	1 kV
3	2 kV
4	4 kV
X	Special

Performance criterion: B

Test Procedure

- 1) For line to line coupling mode, provide a 0.5 kV 1.2/50us voltage surge (at open-circuit condition).
- 2) At least 5 positive and 5 negative (polarity) tests with a maximum 1/min repetition rate are conducted during test.
- 3) Different phase angles are done individually.
- 4) Record the EUT operating situation during compliance test and decide the EUT immunity criterion for above each test.

Test Data and Setup Photo

Environmental Conditions

Temperature:	25 °C
Relative Humidity:	50 %
ATM Pressure:	101.0 kPa

The testing was performed by Lebron Wang on 2011-09-15.

Test Mode: Talking

- 1) Adapter power supply:

Table 1: AC mains power input port

Level	Voltage	Poll	Path	Pass	Fail
1	0.5kV	±	L-N	A	/
2	1kV	±	L-N	A	/
3	2kV	±	L-PE, N-PE	/	/
4	4kV	±	L-N, L-PE, N-PE	/	/

Table 2: RJ45 port

Level	Voltage	Poll	Path	Pass	Fail
1	0.5kV	±	Line-Ground	A	/
2	1kV	±	Line-Ground	A	/
3	2kV	±	Line-Line, Line-Ground	/	/
4	4kV	±	Line-Line, Line-Ground	/	/

AC mains Port



RJ45 port



Test Setup Photos

2) PoE power supply:

Table 1: AC mains power input port

Level	Voltage	Poll	Path	Pass	Fail
1	0.5kV	±	L-N,L-PE, N-PE,L-N-PE	A	/
2	1kV	±	L-N,L-PE, N-PE,L-N-PE	A	/
3	2kV	±	L-PE, N-PE,L-N-PE	A	/
4	4kV	±	L-N, L-PE, N-PE	/	/

Table 2: RJ45 port

Level	Voltage	Poll	Path	Pass	Fail
1	0.5kV	±	Line-Ground	A	/
2	1kV	±	Line-Ground	A	/
3	2kV	±	Line-Line, Line-Ground	/	/
4	4kV	±	Line-Line, Line-Ground	/	/

AC mains Port



RJ45 port

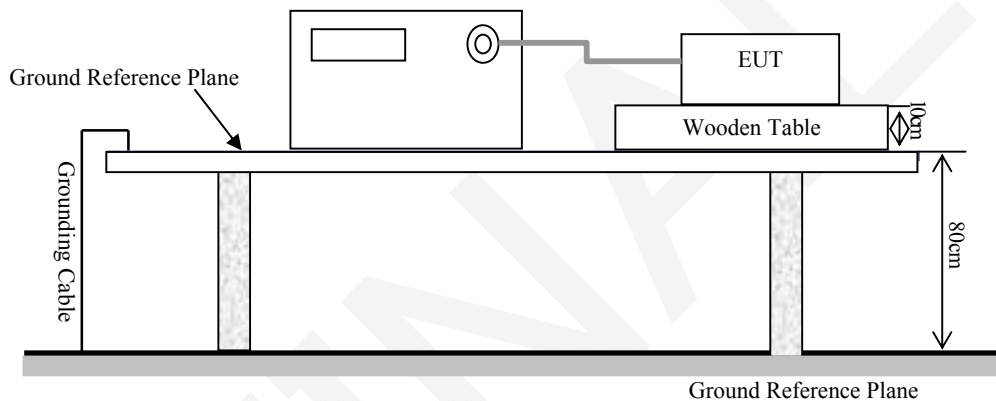


Test Setup Photos

EN 55024 §4.2.6-VOLTAGE DIPS AND INTERRUPTIONS (IEC 61000-4-11)**Test Equipment**

Manufacturer	Description	Model	Serial Number	Calibration Date	Calibration Due Date
EM Test	Ultra Compact Generator	UCS500-N5	V0939105172	2011-07-04	2012-07-03
EM Test	Auto-transformer	MV2616	V0939105173	2011-07-04	2012-07-03

* **Statement of Traceability:** Bay Area Compliance Laboratories Corp. (Shenzhen) attests that all calibrations have been performed in accordance to requirements that traceable to National Primary Standards and International System of Units (SI).

Test Setup**Test Standard**

EN 55024:2010 (IEC 61000-4-11:2004)
Test levels and Performance Criterion

Test Level

Test Level	Voltage dip and short interruptions %UT	Duration (Periods)	Performance Criterion
1	>95	0.5	B
2	30	25	C
3	>95	250	C

Test Procedure

- 1) The interruption is introduced at selected phase angles with specified duration.
- 2) Record any degradation of performance.

Test Data and Setup Photo**Environmental Conditions**

Temperature:	25 °C
Relative Humidity:	50 %
ATM Pressure:	101.0 kPa

The testing was performed by Lebron Wang on 2011-09-15.

Test Mode: Talking

1) Adapter power supply:

Level	U2 (% Reduction)	Td(Periods)	Phase Angle	N	Pass	Fail
1	>95	0.5	0/90/180/270	3	A	/
2	30	25	0/90/180/270	3	B	/
3	>95	250	0/90/180/270	3	B	/



Test Setup Photo

2) PoE power supply:

Level	U2 (% Reduction)	Td(Periods)	Phase Angle	N	Pass	Fail
1	>95	0.5	0/90/180/270	3	A	/
2	30	25	0/90/180/270	3	A	/
3	>95	250	0/90/180/270	3	B	/



Test Setup Photo

EN 61000-3-2-HARMONIC CURRENT EMISSIONS

According to EN 61000-3-2:2006 + A1:2009 + A2:2009 section 7: Equipment with a rated power of 75 W or less, other than discharge lighting equipment, are not included in this standard.

FINAL

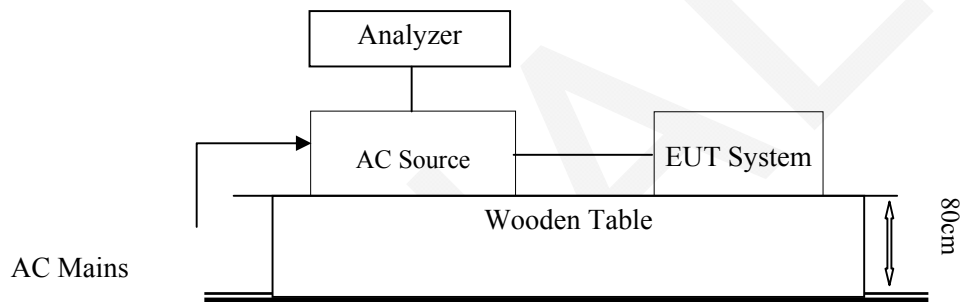
EN 61000-3-3- VOLTAGE FLUCTUATION AND FLICKER

Test Equipment

Manufacturer	Description	Model	Serial Number	Calibration Date	Calibration Due Date
EM Test	Harmonic/Flicker Analyzer	DPA 500N	V0939105176	2010-11-11	2011-11-10
EM Test	AC Source	ACS500	1101-02	2011-03-25	2012-03-24

* **Statement of Traceability:** Bay Area Compliance Laboratories Corp. (Shenzhen) attests that all calibrations have been performed in accordance to requirements that traceable to National Primary Standards and International System of Units (SI).

Test System Setup



Test Standard

EN 61000-3-3:2008

Flicker Test Limits :

The limits shall be applicable to voltage fluctuations and flicker at the supply terminals of the equipment under test, measured or calculated according to clause 4 under test conditions described in clause 6 and annex A. Tests made to prove compliance with the limits are considered to be type tests.

The following limits apply:

- the value of Pst shall not be greater than 1,0;
- the value of Plt shall not be greater than 0,65;
- the value of d(t) during a voltage change shall not exceed 3,3 % for more than 500 ms;
- the relative steady-state voltage change, dc, shall not exceed 3,3 %;
- the maximum relative voltage change dmax, shall not exceed
 - a) 4 % without additional conditions;
 - b) 6 % for equipment which is:
 - switched manually, or
 - switched automatically more frequently than twice per day, and also has either a delayed restart (the delay being not less than a few tens of seconds), or manual restart, after a power supply interruption.

Note: The cycling frequency will be further limited by the Pst and Plt limit. For example: a dmax of 6 % producing a rectangular voltage change characteristic twice per hour will give a Plt of about 0,65.

c) 7 % for equipment which is

- attended whilst in use (for example: hair dryers, vacuum cleaners, kitchen equipment such as mixers, garden equipment such as lawn mowers, portable tools such as electric drills), or
- switched on automatically, or is intended to be switched on manually, no more than twice per day, and also has either a delayed restart (the delay being not less than a few tens of seconds) or manual restart, after a power supply interruption.

In the case of equipment having several separately controlled circuits in accordance with 6.6, limits b) and c) shall apply only if there is delayed or manual restart after a power supply interruption; for all equipment with automatic switching which is energized immediately on restoration of supply after a power supply interruption, limits a) shall apply; for all equipment with manual switching, limits b) or c) shall apply depending on the rate of switching. Pst and Plt requirements shall not be applied to voltage changes caused by manual switching. The limits shall not be applied to voltage changes associated with emergency switching or emergency interruptions.

Test Data and Setup Photo

Environmental Conditions

Temperature:	25°C
Relative Humidity:	50 %
ATM Pressure:	100.0 kPa

Date of test:	14:04 31.Jul 2011
Tester:	Lebron Wang
Standard used:	EN/IEC 61000-3-3 Flicker
Short time (Pst):	10 min
Observation time:	10 min (1 Flicker measurement)
Flicker meter:	230V / 50Hz
Customer:	YEALINK (XIAMEN) NETWORK TECHNOLOGY CO., LTD.
E. U. T.:	IP PHONE
Model:	SIP-T26P
Test Mode:	Talking (adapter power supply)

Maximum Flicker results

	EUT values	Limit	Result
Pst	0.028	1.00	PASS
dc [%]	0.028	0.65	PASS
dmax [%]	0.012	3.30	PASS
dt [s]	0.274	4.00	PASS

**Test Setup Photo**

Date of test:	14:07 31.Jul 2011
Tester:	Lebron Wang
Standard used:	EN/IEC 61000-3-3 Flicker
Short time (Pst):	10 min
Observation time:	10 min (1 Flicker measurement)
Flicker meter:	230V / 50Hz
Customer:	YEALINK (XIAMEN) NETWORK TECHNOLOGY CO., LTD.
E. U. T.:	IP PHONE
Model:	SIP-T26P
Test Mode:	Talking (PoE power supply)

Maximum Flicker results

	EUT values	Limit	Result
Pst	0.028	1.00	PASS
dc [%]	0.028	0.065	PASS
dmax [%]	0.013	3.30	PASS
dt [s]	0.054	4.00	PASS



Test Setup Photo

EXHIBIT A - PRODUCT LABELING

Label Specification



Specifications: The marking set out above must be affixed to the apparatus or to its data plate and have a minimum height of 5 mm. The elements should be easily readable and indelible. They may be placed anywhere on the apparatus case or in its battery compartment. No tool should be needed to view the marking.

Label Location on EUT



EXHIBIT B - EUT PHOTOGRAPHS

EUT – All View



EUT – Top View 1



EUT – Top View 2



EUT – Bottom View



EUT – Front View



EUT – Rear View



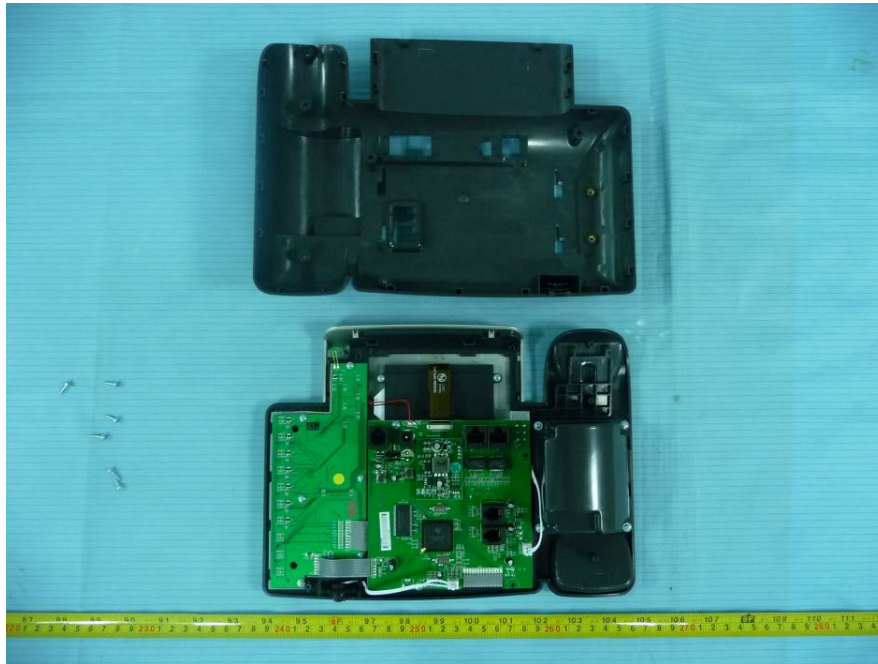
EUT – Left View



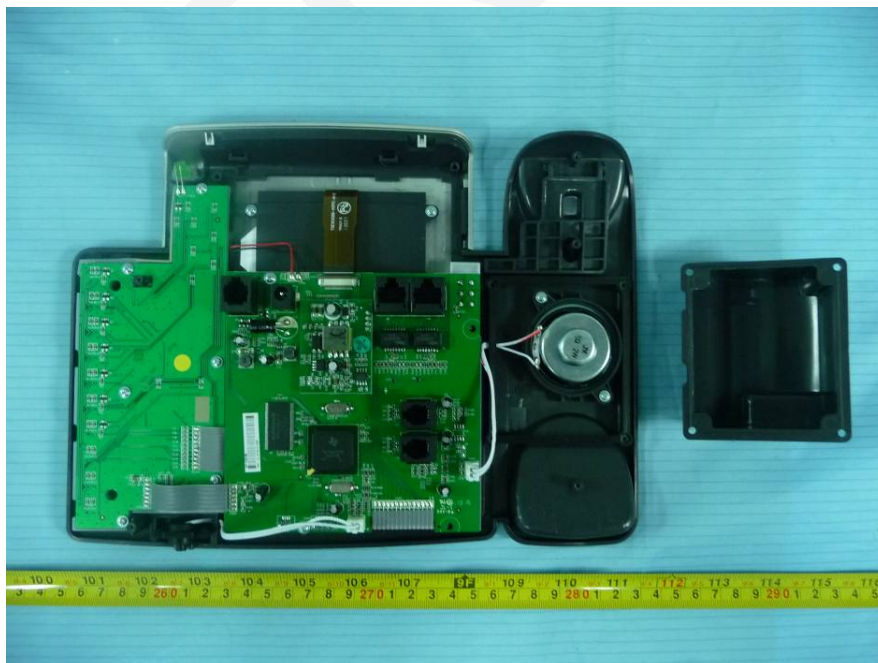
EUT – Right View



EUT – Cover off View 1



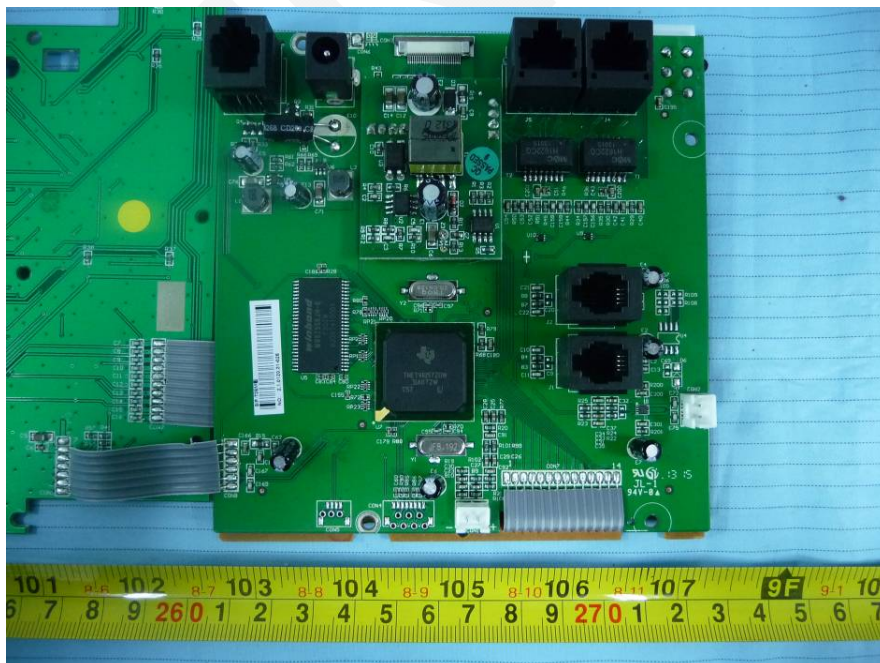
EUT – Cover off View 2



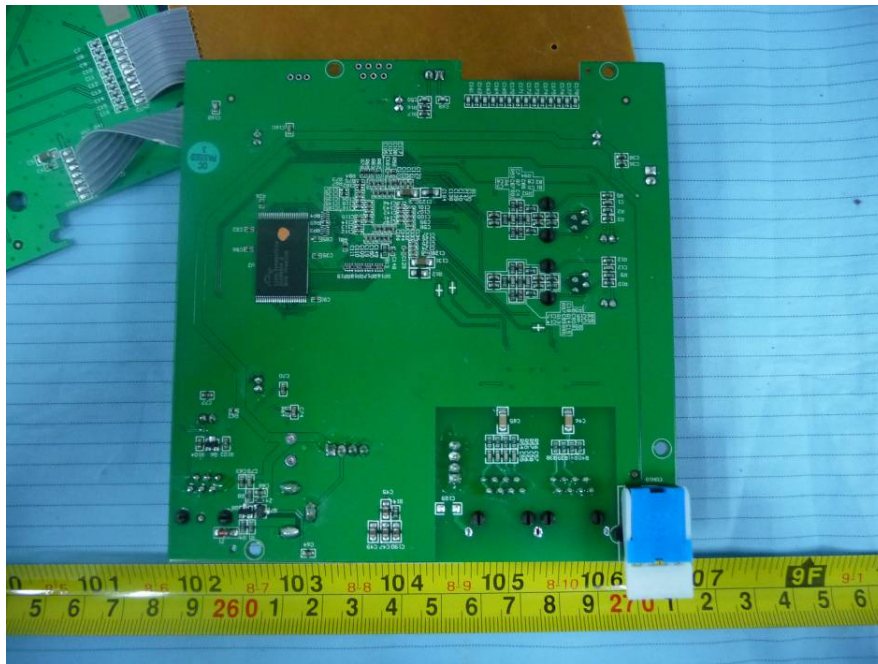
EUT – Handset Cover off View



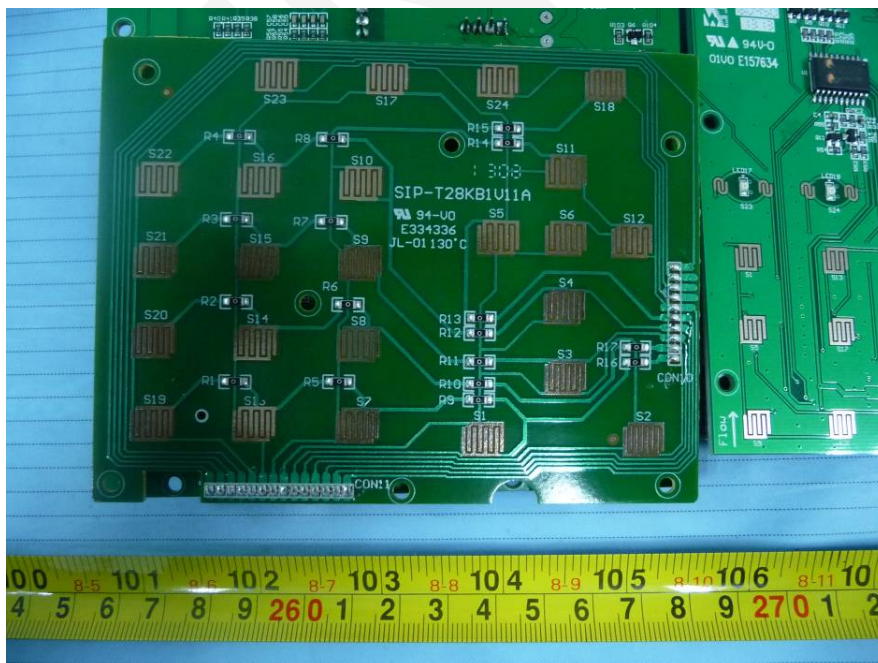
EUT – Main Board Top View



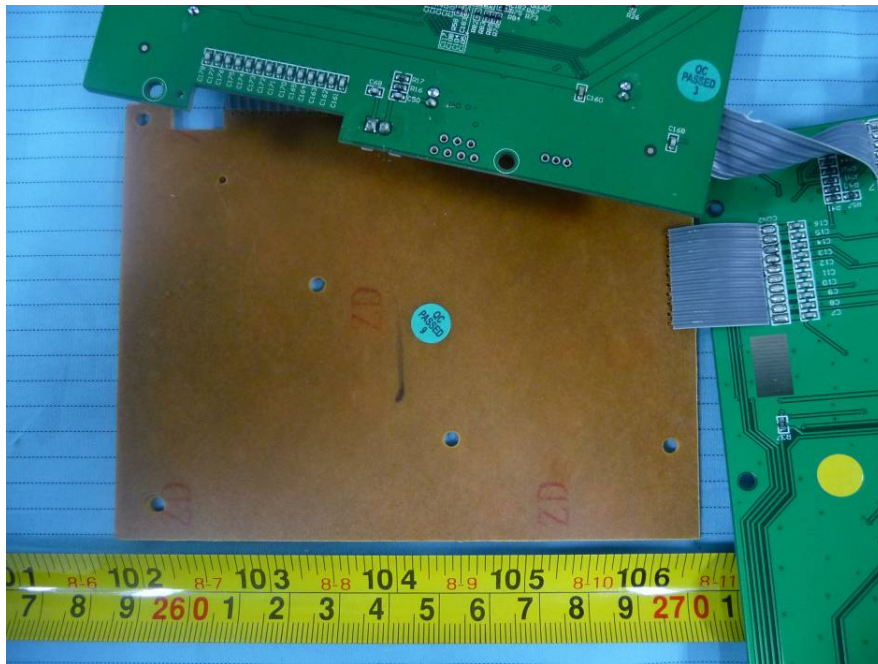
EUT – Main Board Bottom View



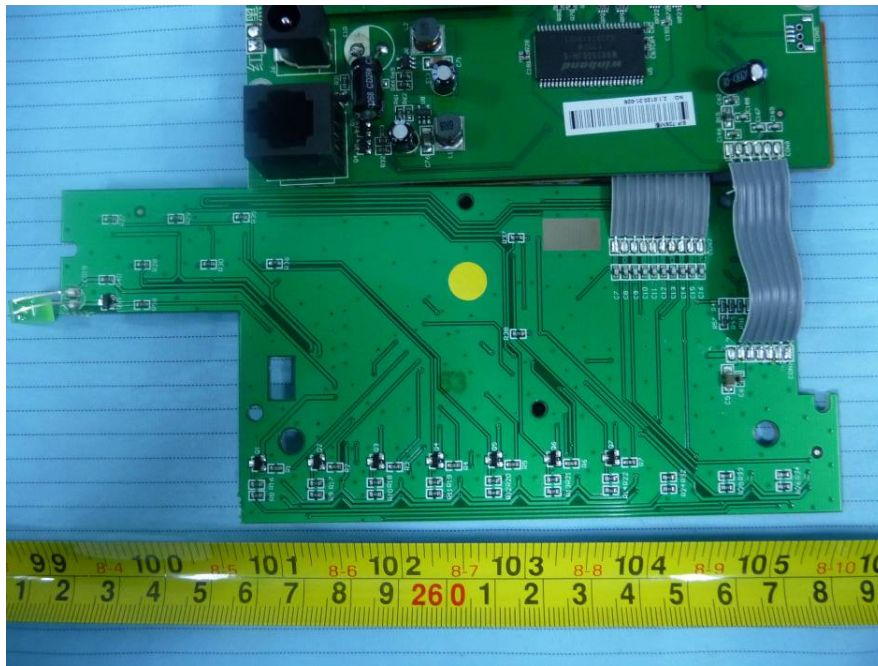
EUT – Key Board 1 Top View



EUT – Key Board 1 Bottom View



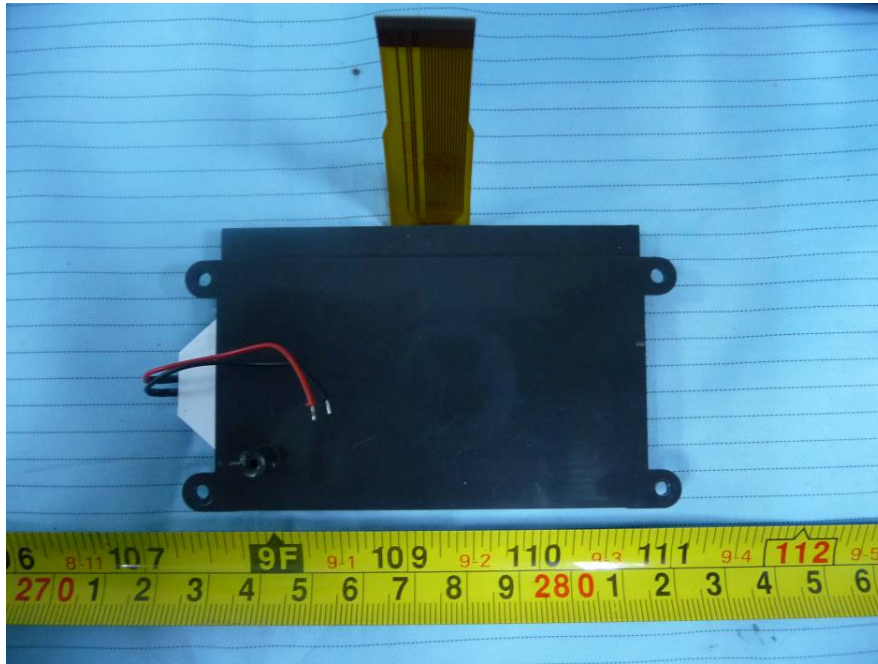
EUT – Key Board 2 Bottom View



EUT – LCD Screen Top View



EUT – LCD Screen Bottom View



EUT – Adapter 1 View



EUT – Adapter 1 Label View



EUT – Adapter 2 Label View



EUT – Adapter 3 Label View



EXHIBIT C - TEST SETUP PHOTOGRAPHS

Conducted Disturbance - Front View (Adapter 1 power supply)



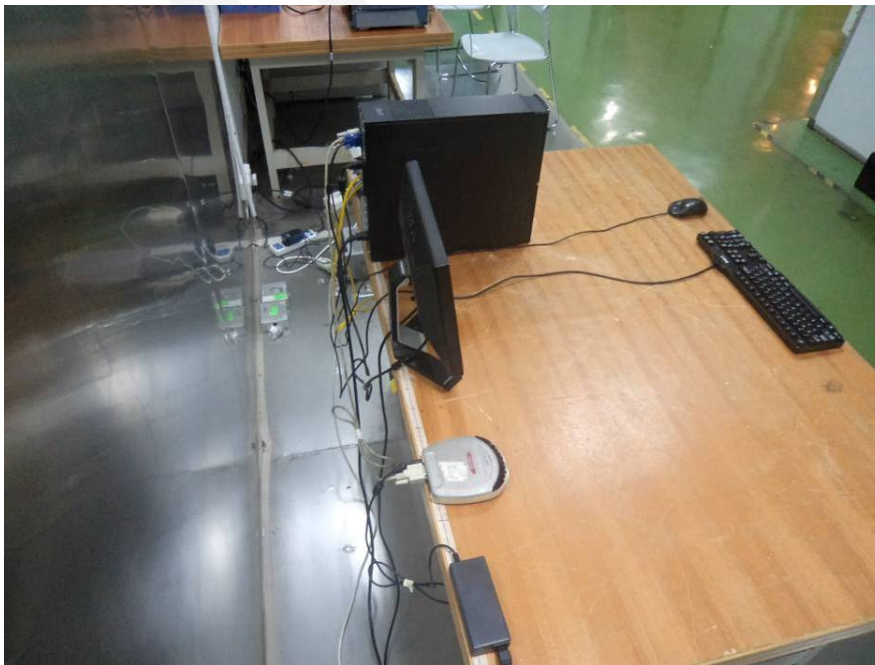
Conducted Disturbance - Side View (Adapter 1 power supply)



Conducted Disturbance - Front View (Adapter 2 power supply)



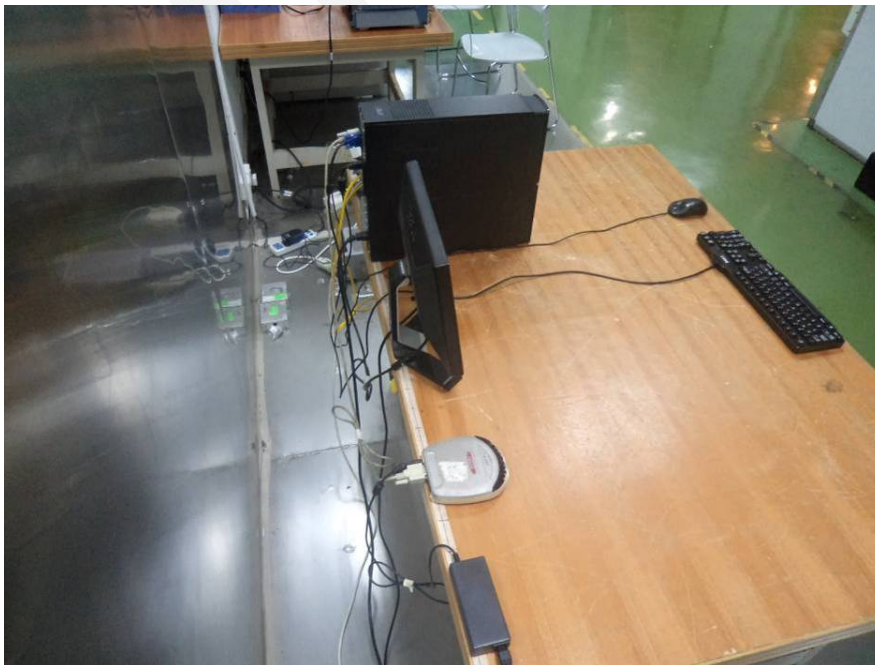
Conducted Disturbance - Side View (Adapter 2 power supply)



Conducted Disturbance - Front View (Adapter 3 power supply)



Conducted Disturbance - Side View (Adapter 3 power supply)



Conducted Disturbance - Front View (PoE power supply)



Conducted Disturbance - Side View (PoE power supply)



Conducted Disturbance - Front View (RJ45 Port)



Conducted Disturbance - Side View (RJ45 Port)



Below 1 GHz: Radiated Disturbance - Front View (Adapter 1 power supply)



Below 1 GHz: Radiated Disturbance - Rear View (Adapter 1 power supply)



Above 1 GHz: Radiated Disturbance - Front View (Adapter 1 power supply)



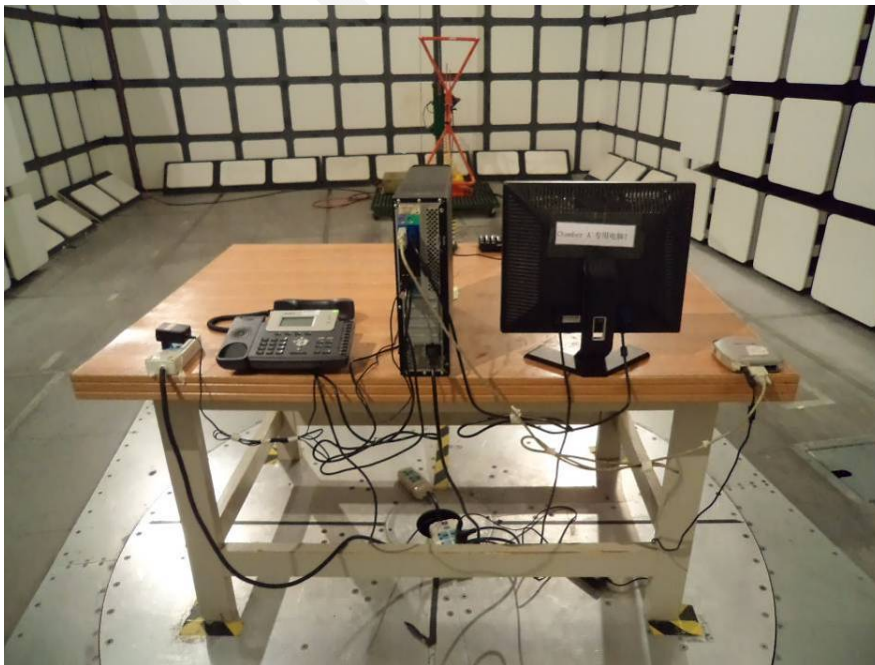
Above 1 GHz: Radiated Disturbance - Rear View (Adapter 1 power supply)



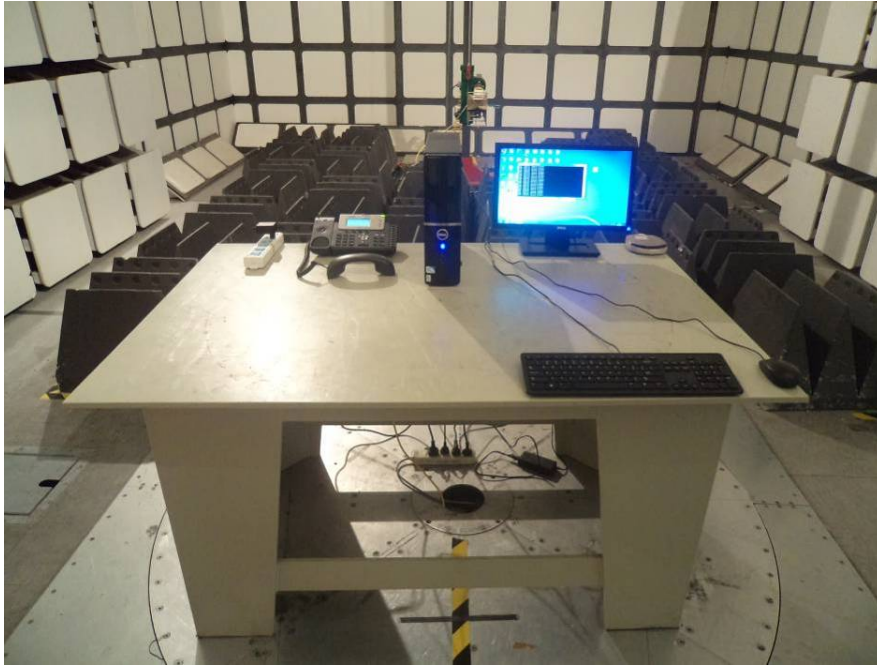
Below 1 GHz: Radiated Disturbance - Front View (Adapter 2 power supply)



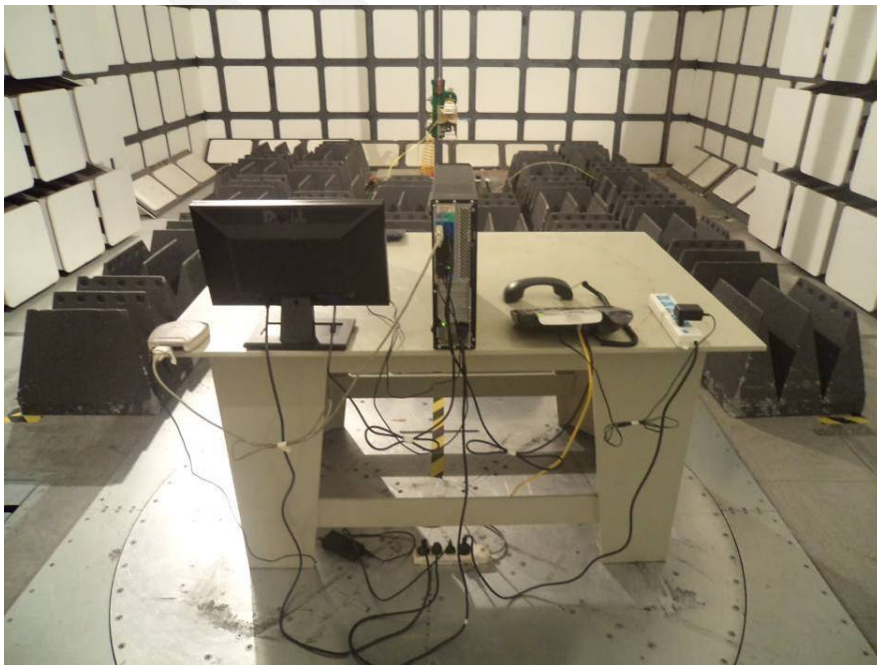
Below 1 GHz: Radiated Disturbance - Rear View (Adapter 2 power supply)



Above 1 GHz: Radiated Disturbance - Front View (Adapter 2 power supply)



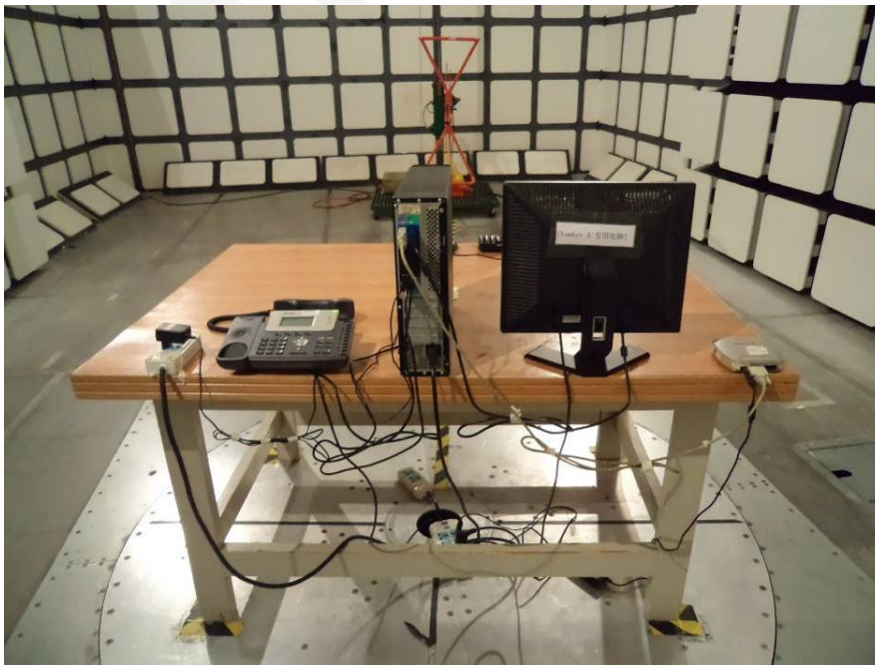
Above 1 GHz: Radiated Disturbance - Rear View (Adapter 2 power supply)



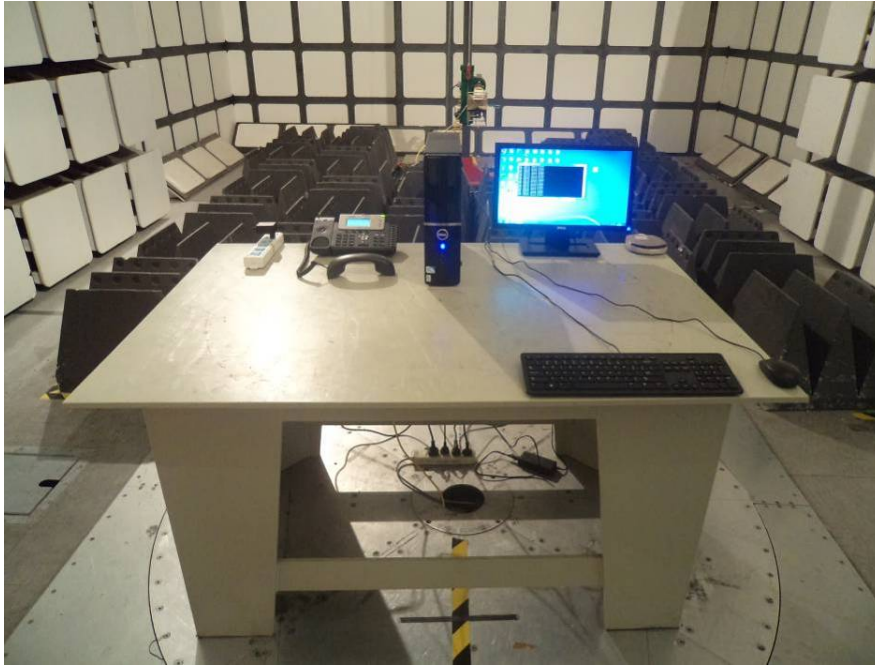
Below 1 GHz: Radiated Disturbance - Front View (Adapter 3 power supply)



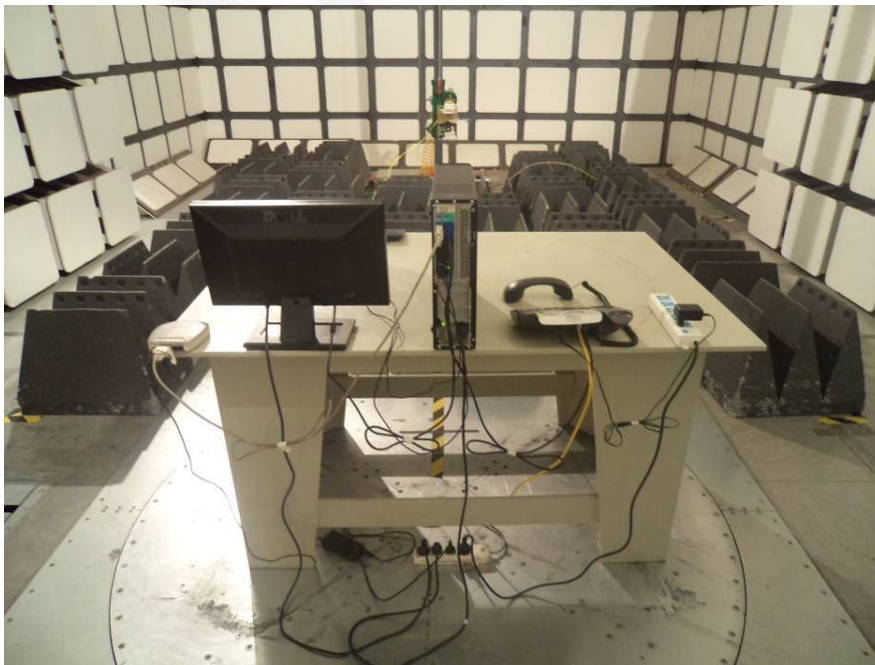
Below 1 GHz: Radiated Disturbance - Rear View (Adapter 3 power supply)



Above 1 GHz: Radiated Disturbance - Front View (Adapter 3 power supply)



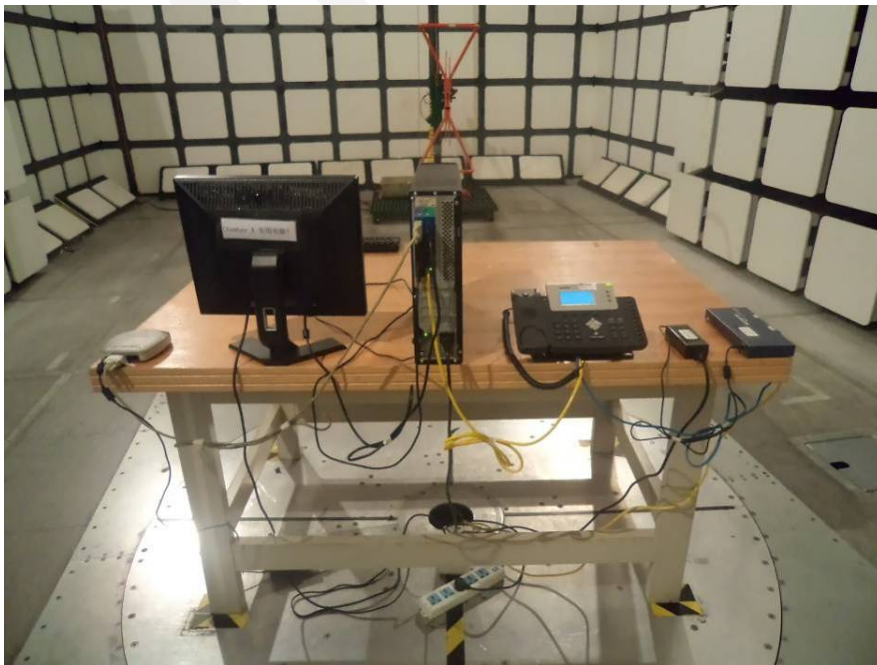
Above 1 GHz: Radiated Disturbance - Rear View (Adapter 3 power supply)



Below 1 GHz: Radiated Disturbance - Front View (PoE power supply)



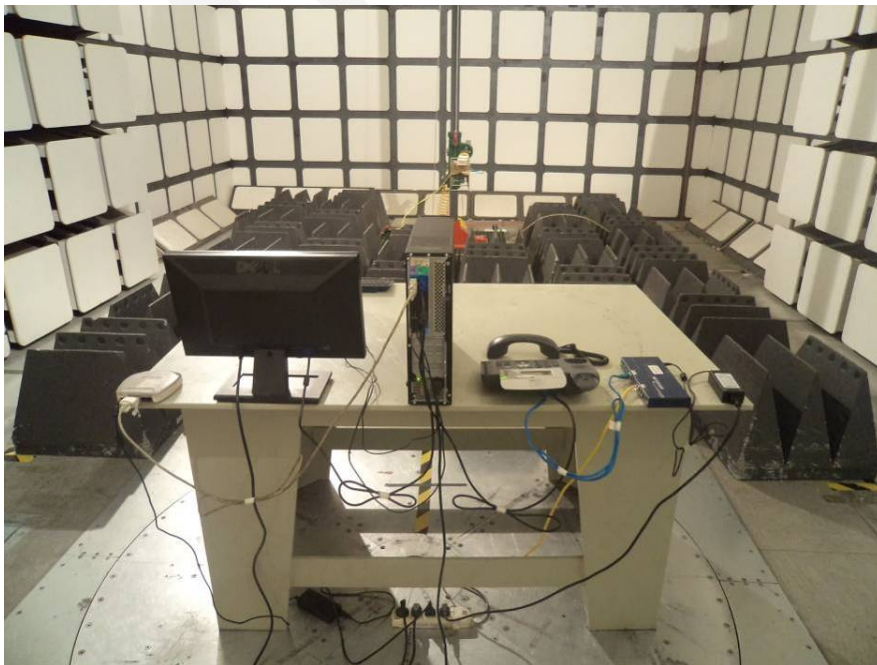
Below 1 GHz: Radiated Disturbance - Rear View (PoE power supply)



Above 1 GHz: Radiated Disturbance - Front View (PoE power supply)



Above 1 GHz: Radiated Disturbance - Rear View (PoE power supply)



PRODUCT SIMILARITY DECLARATION LETTER



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Tel: 86-592-5702000 Fax: 86-592-5702455

2013-6-21

Product Similarity Declaration Letter

To Whom It May Concern,

We, Yealink (Xiamen) Network Technology Co., LTD. hereby declare that our product IP Phone, the model SIP-T26P and SIP-T26 are electrically identical, they have the same PCB layout and schematic, the only difference is the model T26P with POE circuit, the model T26 without POE circuit. SIP-T26P was tested by BACL.

Please contact me if you have any question.

Signature:

A handwritten signature in black ink that reads "Stone Lu".

Stone Lu

Vice General Manager

******* END OF REPORT *******